
ENEE 359a
Lecture/s 12-15
Sequential Logic

Bruce Jacob

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ECE Dept.

SLIDE 1

ENEE 359a

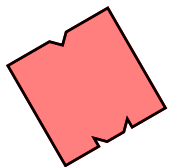
Digital VLSI Design

Sequential Logic

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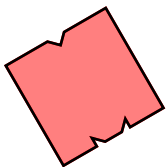
Credit where credit is due:

Slides contain original artwork (© Jacob 2004) as well as material taken liberally from Irwin & Vijay's CSE477 slides (PSU), Schmit & Strojwas's 18-322 slides (CMU), Dally's EE273 slides (Stanford), Wolf's slides for *Modern VLSI Design*, and/or Rabaey's slides (UCB).



Overview

- **Transmission gates**
- **Basic storage-cell concepts**
- **Metastability**
- **Static latches & registers, brief primer on dynamic logic, dynamic latches & registers, trading off complexity in individual memory elements vs. complexity in clock-delivery network**
- **Pipelining**



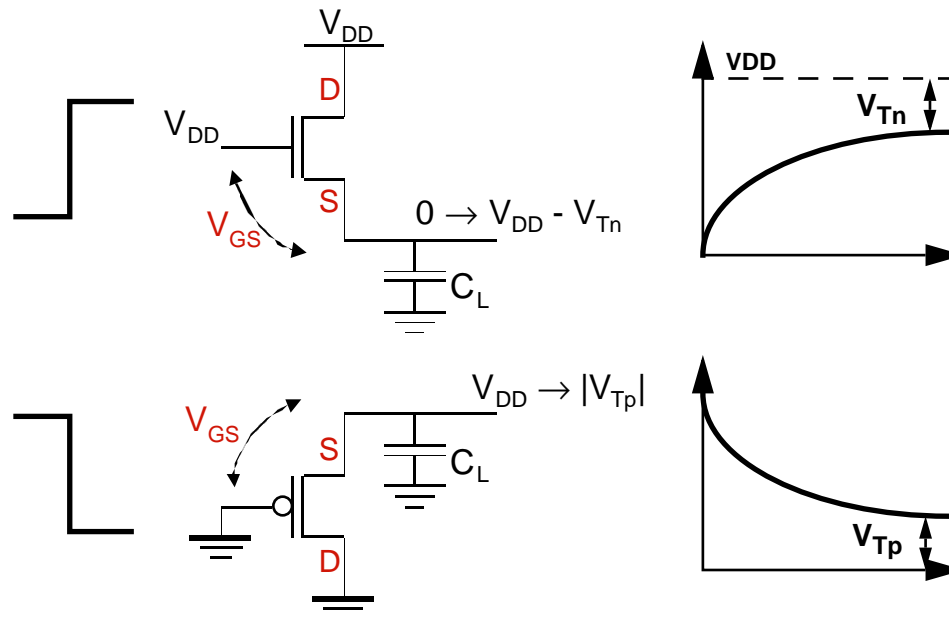
The Transmission Gate

Basic idea: reduce number of transistors in design by allowing inputs to drive not only *gate* terminals but also *source/drain* terminals.

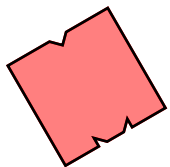
(similar in this regard to *pass-transistor* logic)

Recall:

- **NMOS will not** pass a “1”
- **PMOS will not** pass a “0”

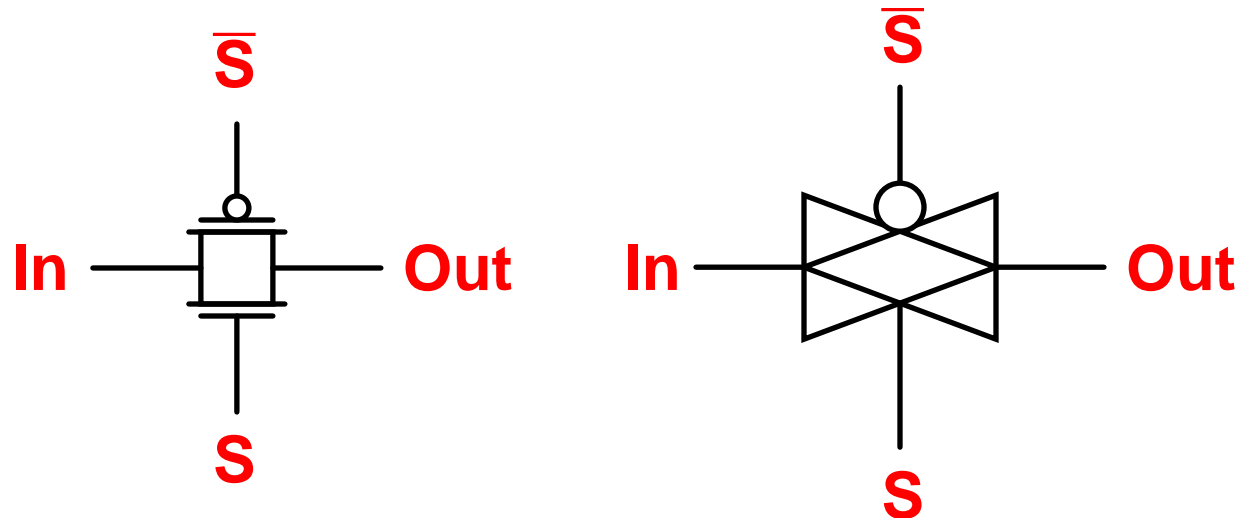


- **Body effect ($V_{BS} \neq 0$) causes $V_{Tn/p}$ to increase**



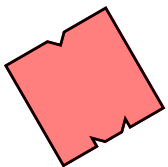
The Transmission Gate

Solution: use both




$$\text{Out} = (S) ? \text{In} : Z;$$

Potential problem: unlike other static logic gates, this can allow output to be *floating* (not connected — thus, easily perturbed by nearby signals such as metal wires above)



The Transmission Gate

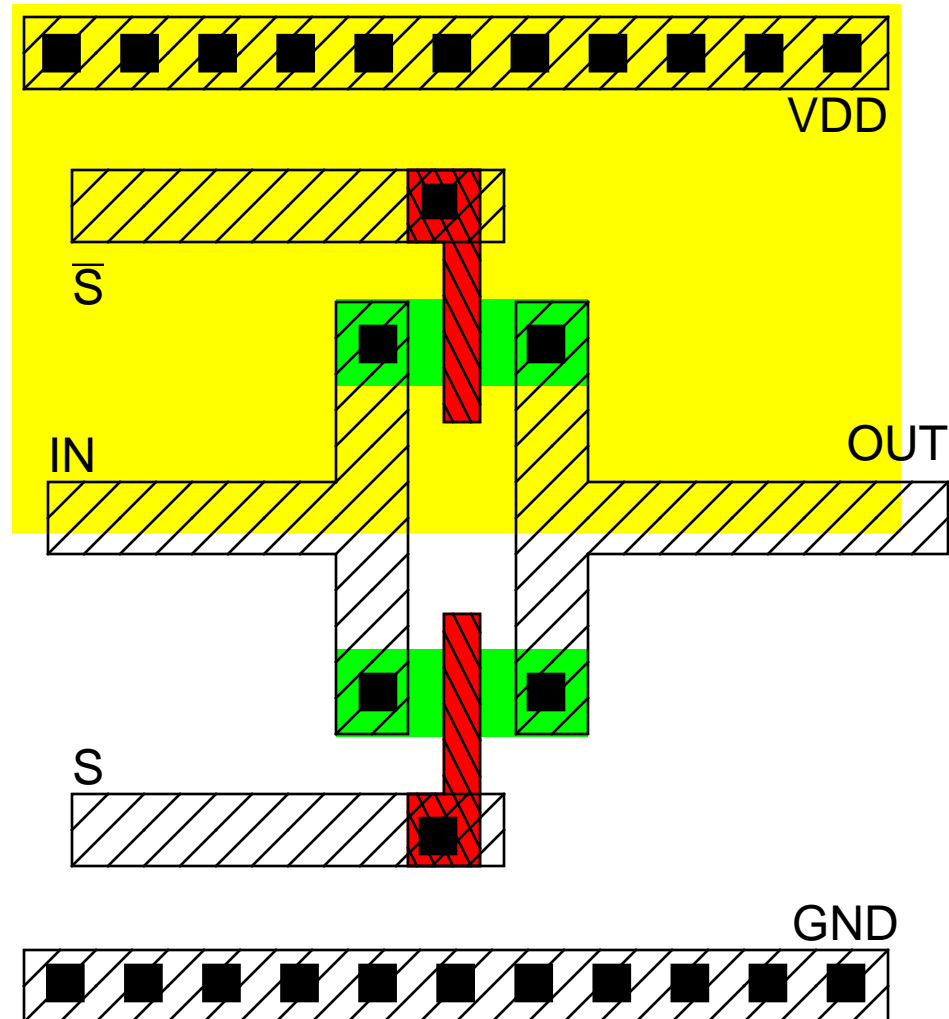
 poly

 metal

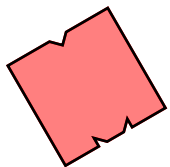
 active

 n-well

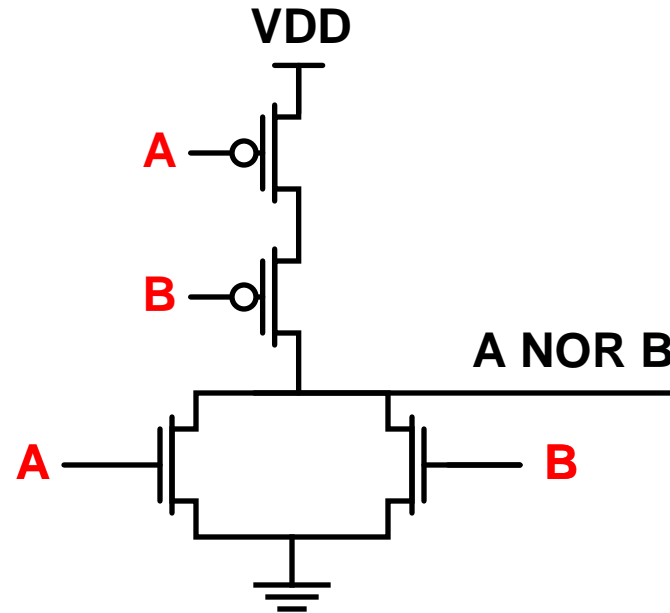
 via



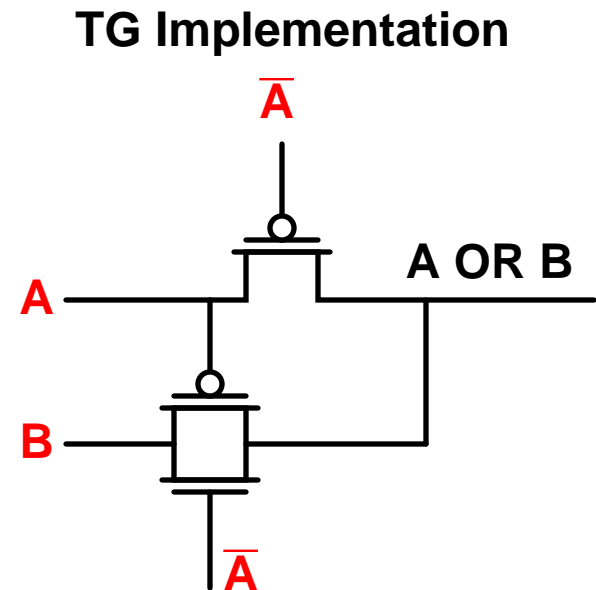
Sometimes standard cell includes S inverter



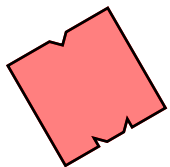
The Transmission Gate



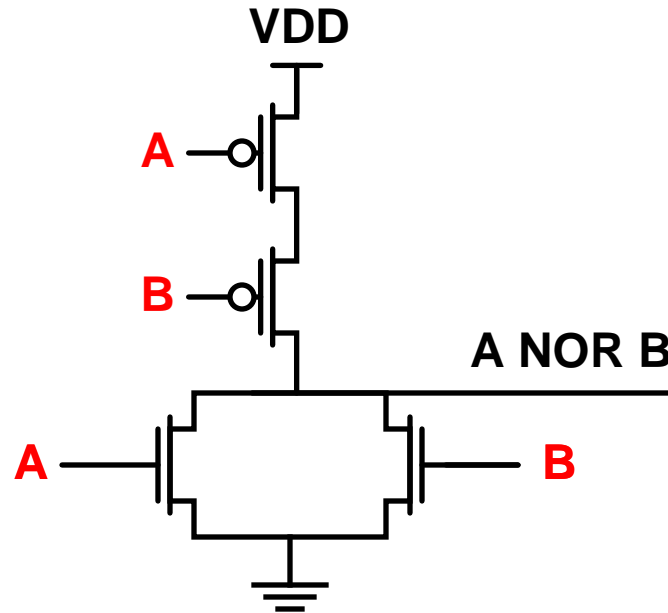
Complementary
Implementation



TG Implementation

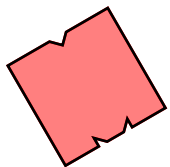
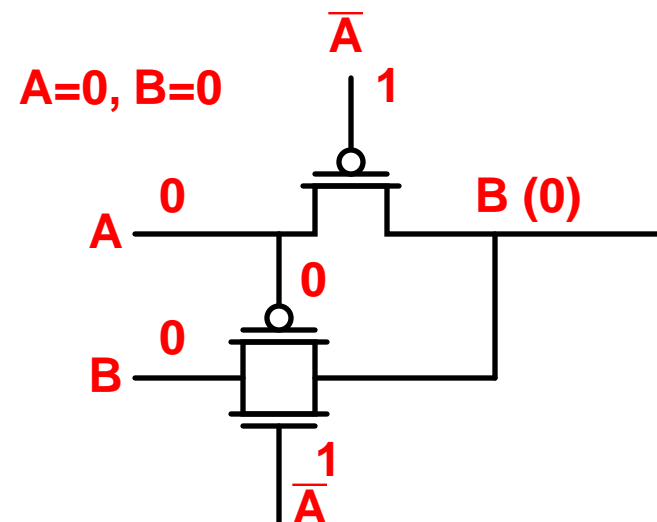


The Transmission Gate

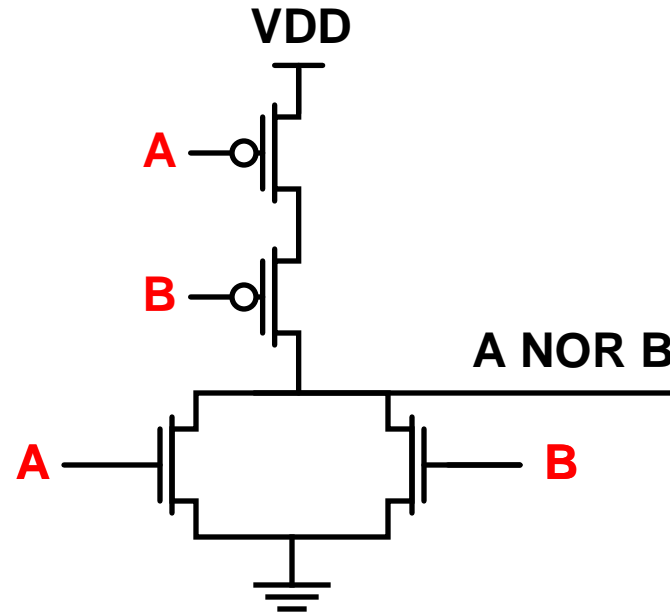


Complementary
Implementation

TG Implementation

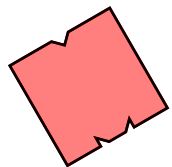
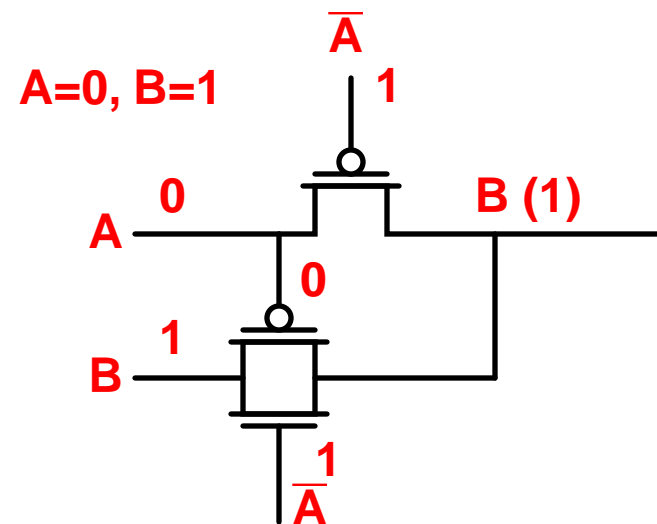


The Transmission Gate

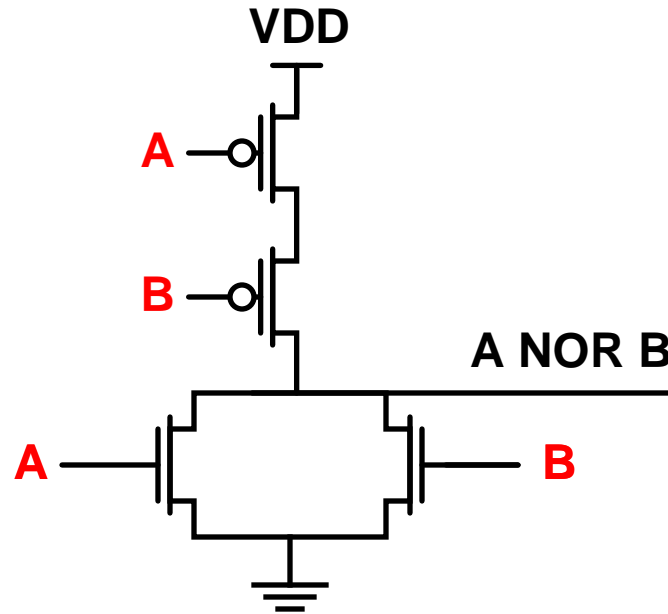


Complementary
Implementation

TG Implementation

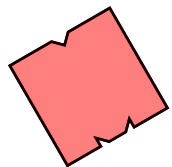
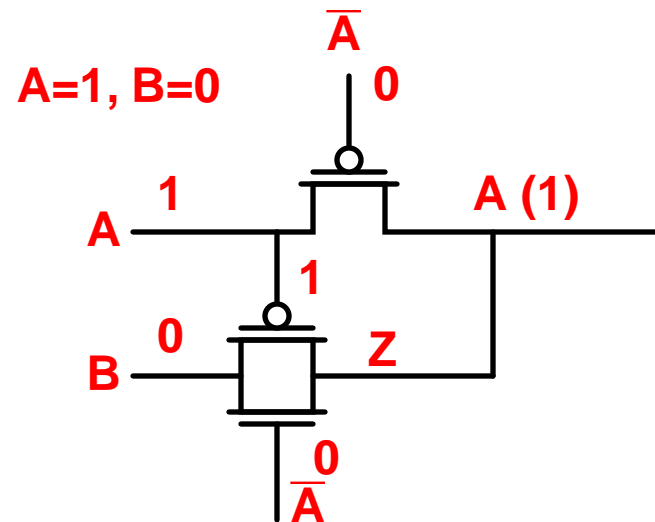


The Transmission Gate

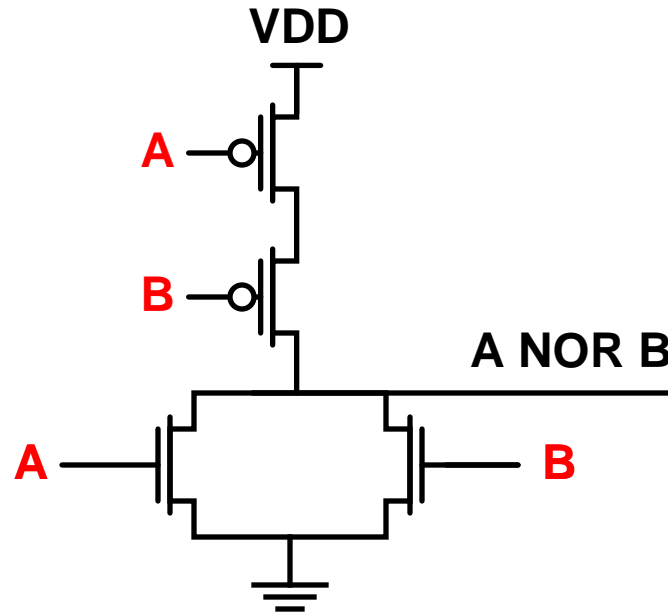


Complementary
Implementation

TG Implementation

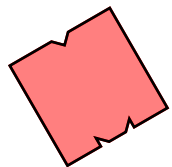
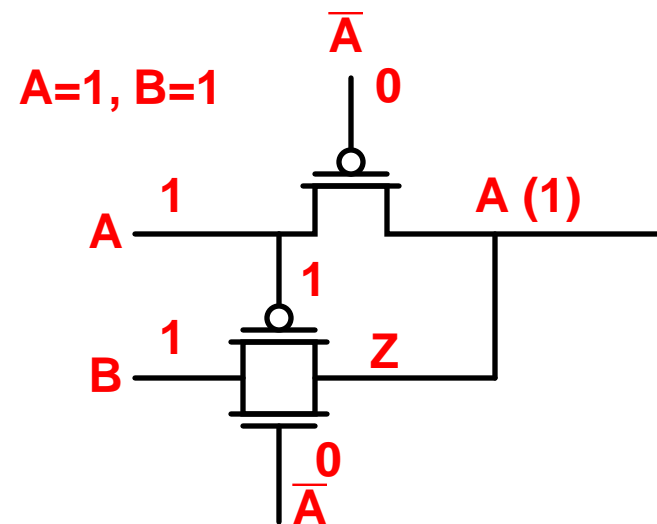


The Transmission Gate

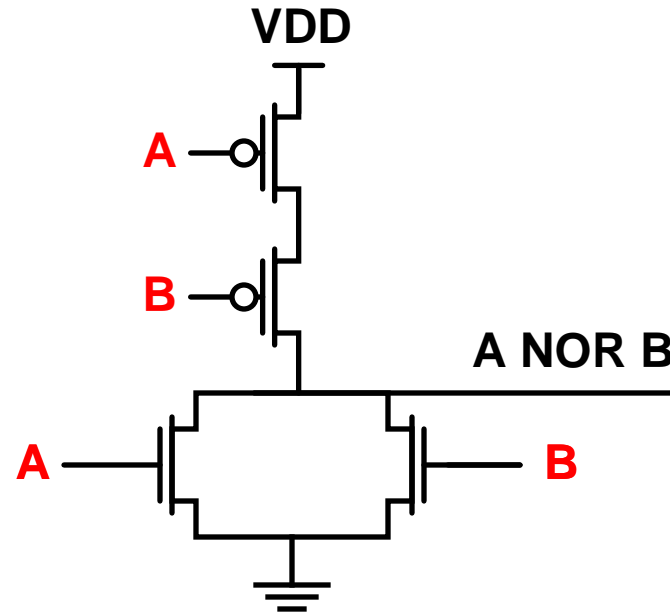


Complementary
Implementation

TG Implementation

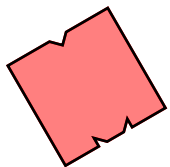
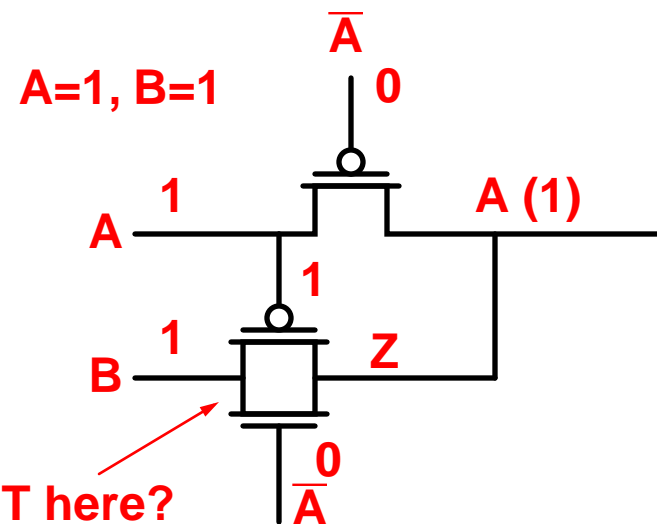


The Transmission Gate

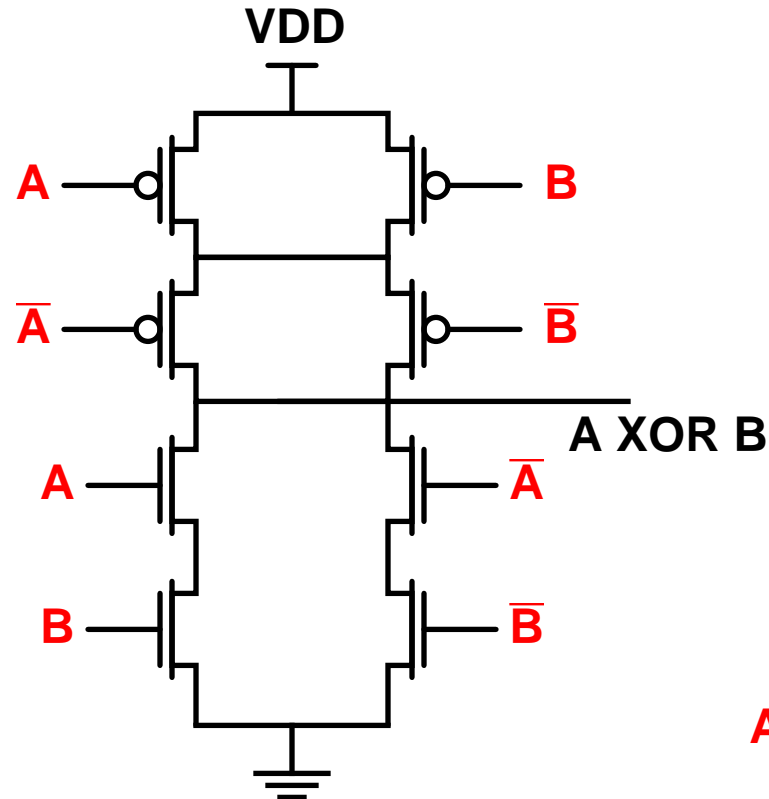


Complementary
Implementation

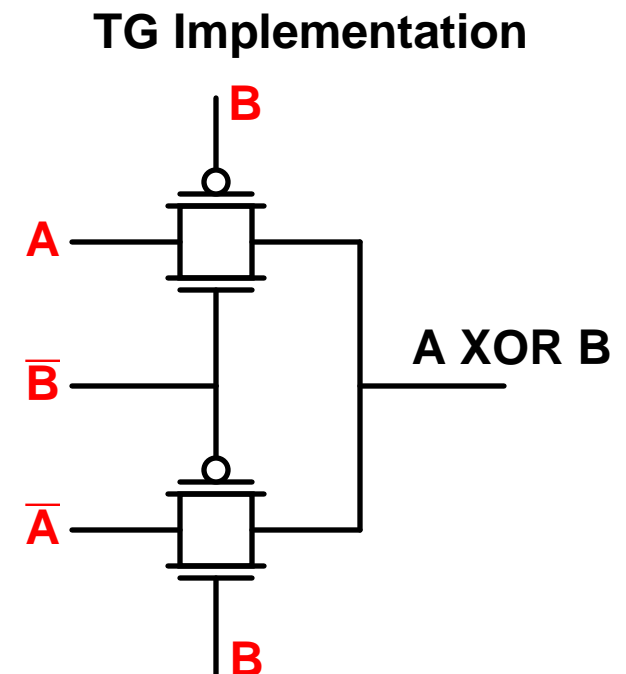
TG Implementation



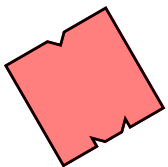
The Transmission Gate



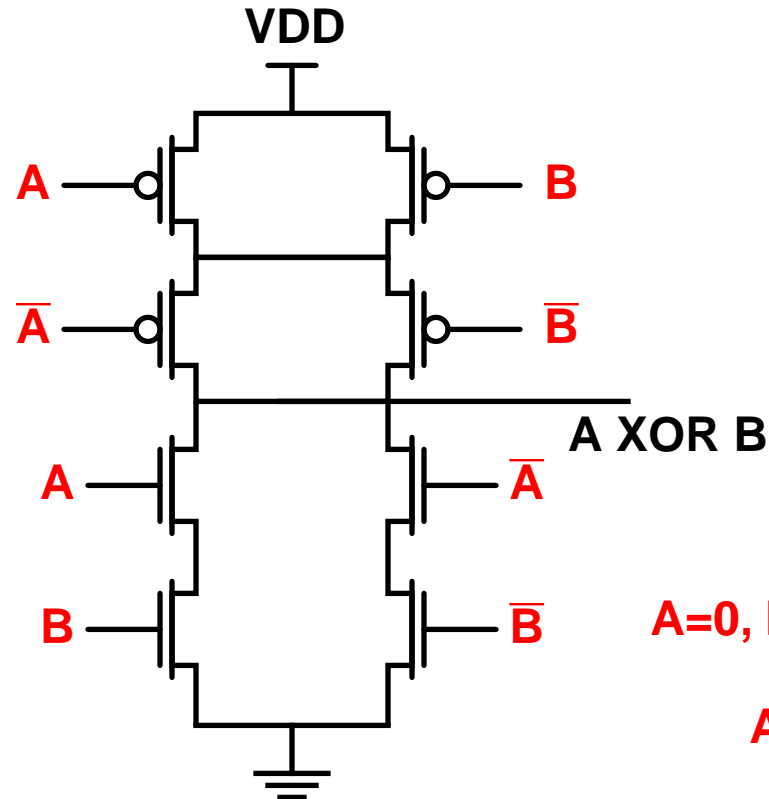
Complementary
Implementation



TG Implementation

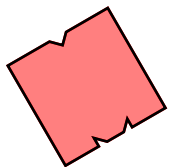
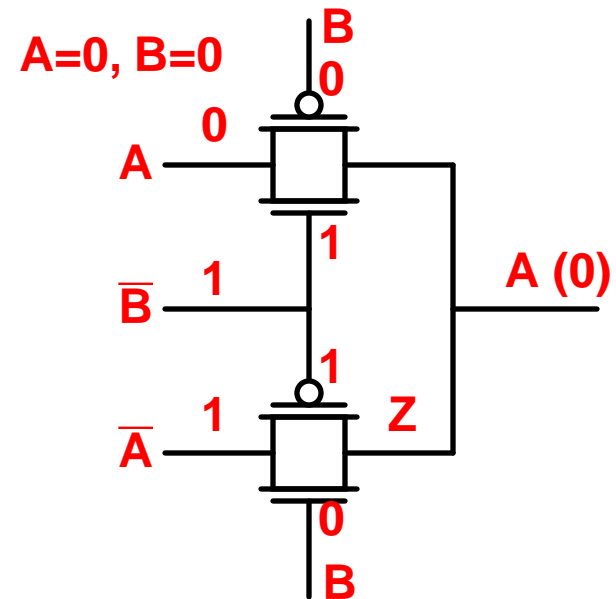


The Transmission Gate

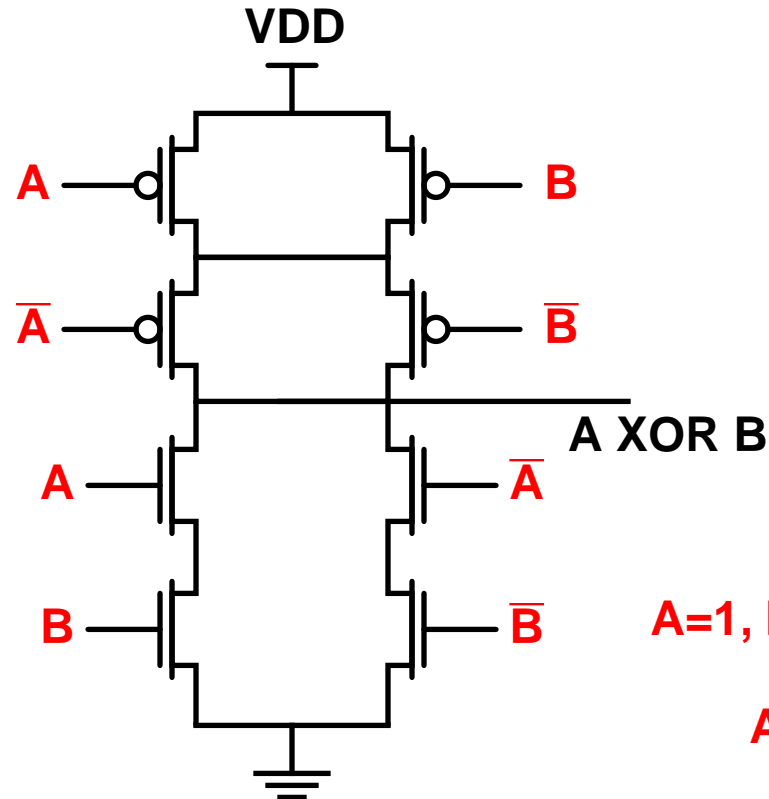


Complementary Implementation

TG Implementation

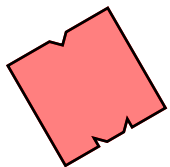
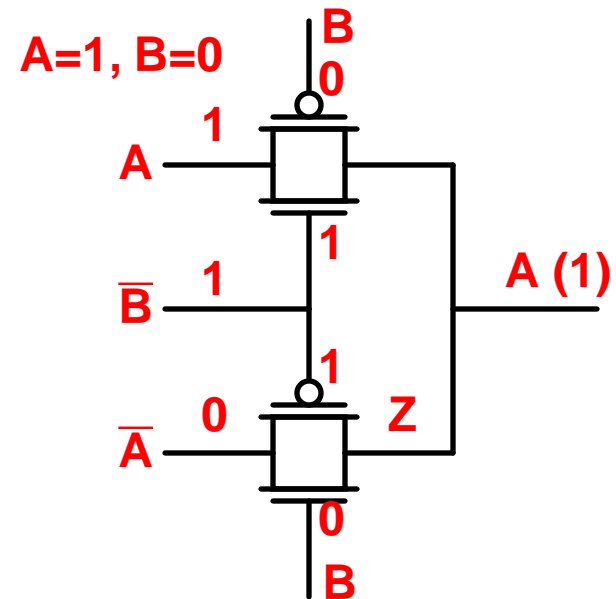


The Transmission Gate

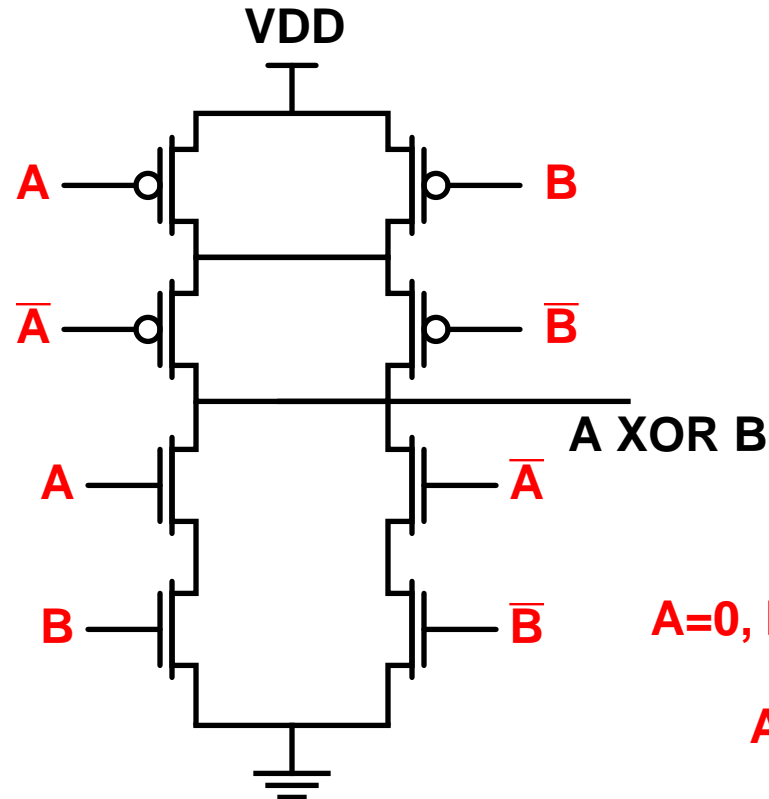


Complementary Implementation

TG Implementation

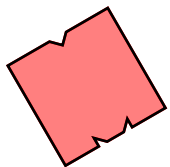
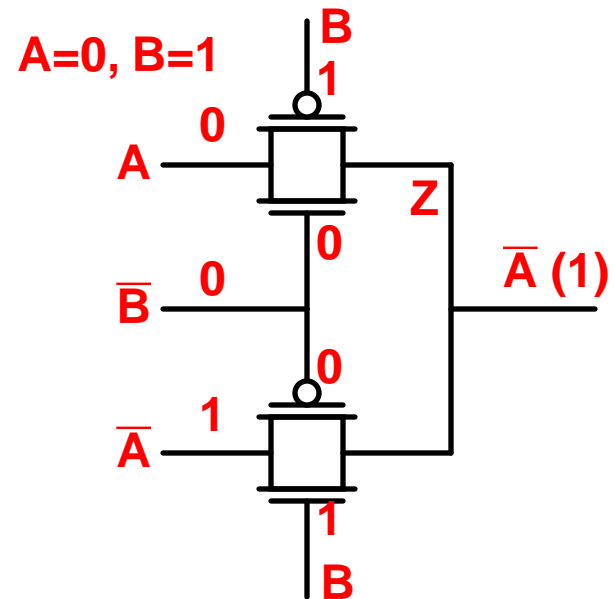


The Transmission Gate

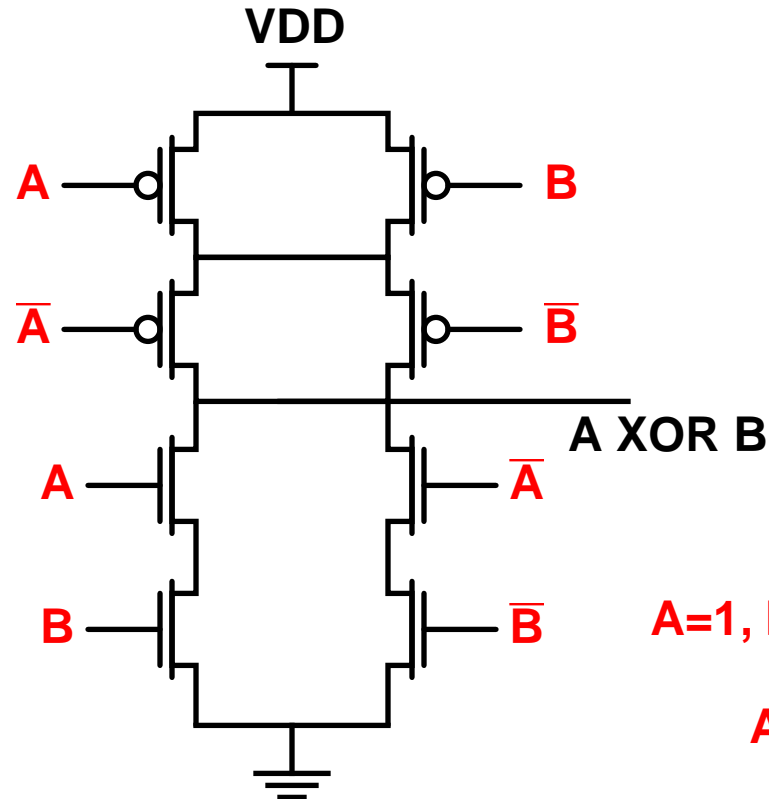


Complementary Implementation

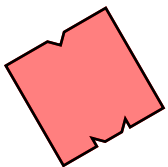
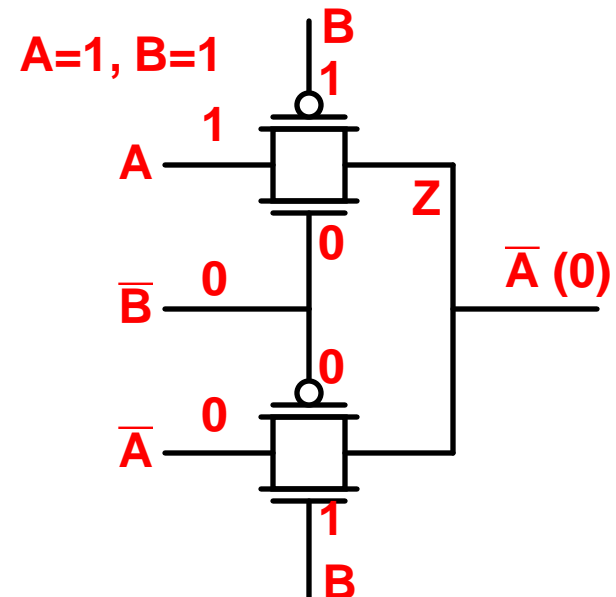
TG Implementation



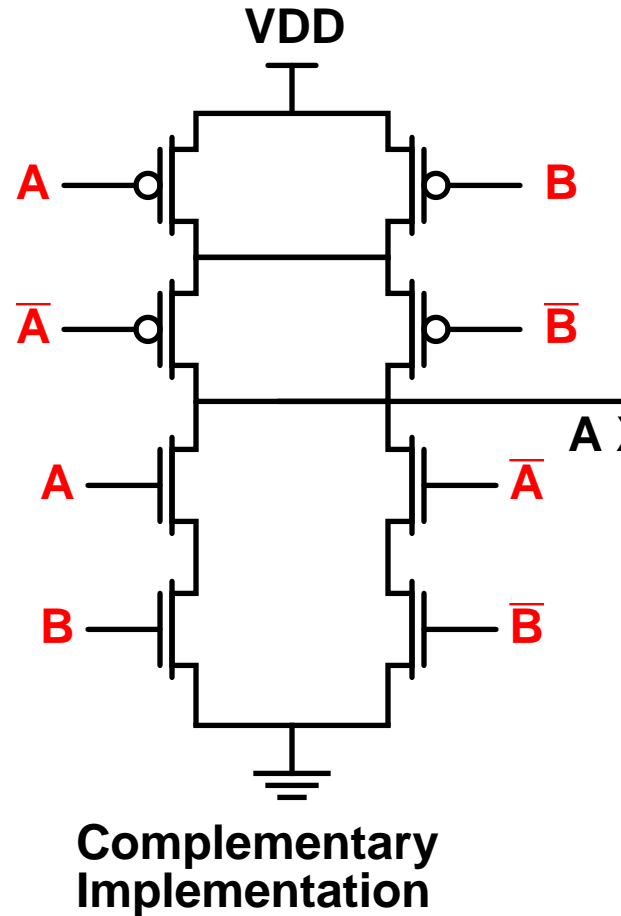
The Transmission Gate



TG Implementation



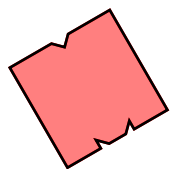
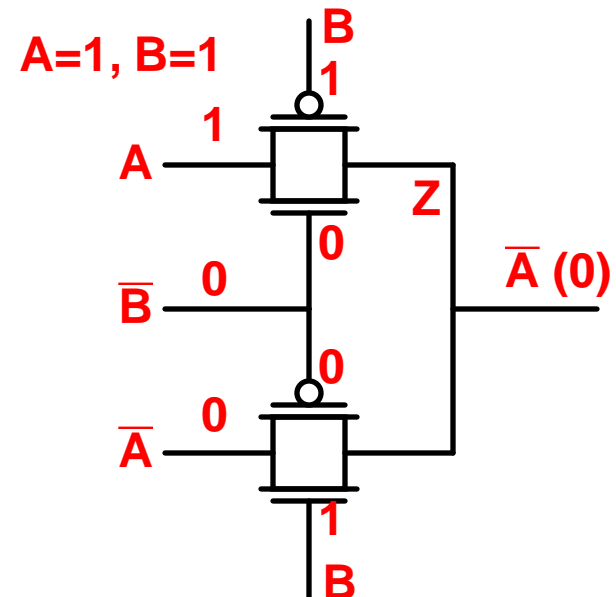
The Transmission Gate



Transmission-gate logic is a huge win for circuits that need XOR/XNOR and similar functions, e.g. full adders

$$\text{XOR} = A\bar{B} + \bar{A}B$$

TG Implementation

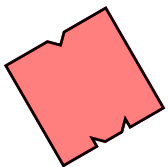


Basic storage-cell concepts

DEFINITIONS (from the book):

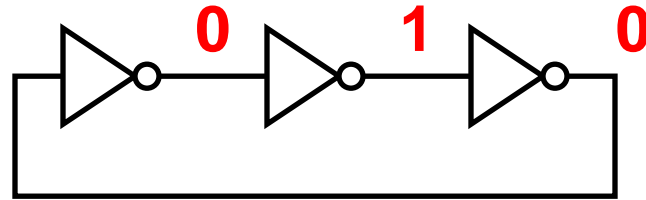
1. **Flip-flop**: bistable component built by cross-coupling logic gates
2. **Latch**: *level-sensistive* storage element
3. **Register**: *edge-triggered* storage element

(the literature on the topic is not consistent in its use of these terms, so beware and try to figure out from context what someone means ...)

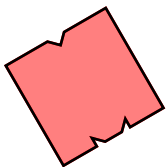


Basic storage-cell concepts

Bistable? Only two stable points on VTC

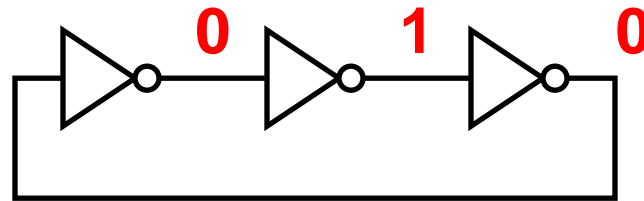


... what happens next?

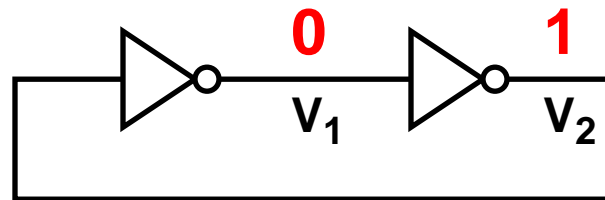


Basic storage-cell concepts

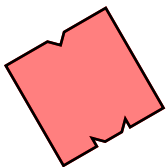
Bistable? Only two stable points on VTC



... what happens next?

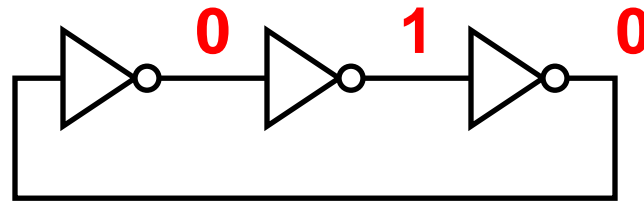


... what happens next?

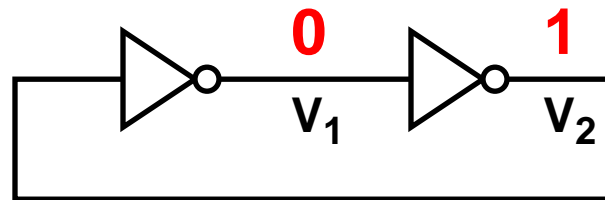


Basic storage-cell concepts

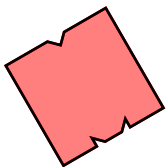
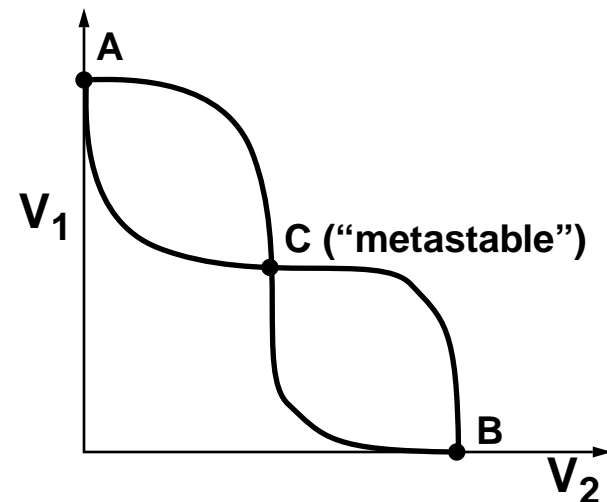
Bistable? Only two stable points on VTC



... what happens next?



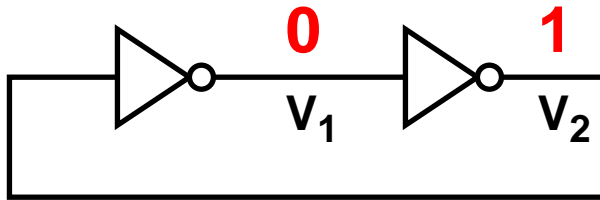
this is a stable circuit
(and, in particular, bistable)



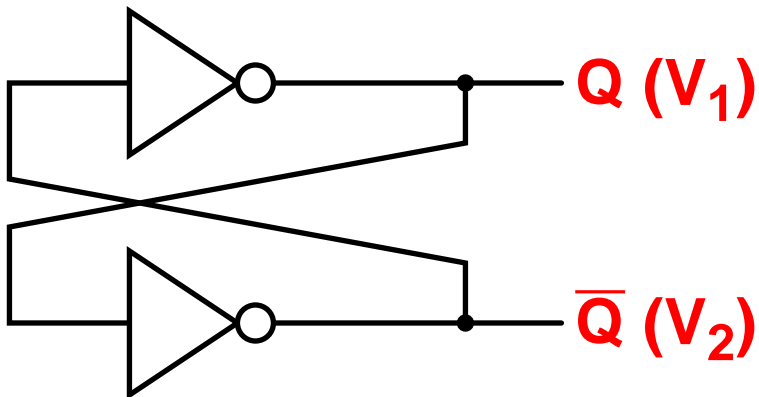
Basic storage-cell concepts

Cross-coupling? Memory as feedback

This:

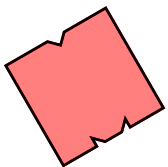


Equals
this:



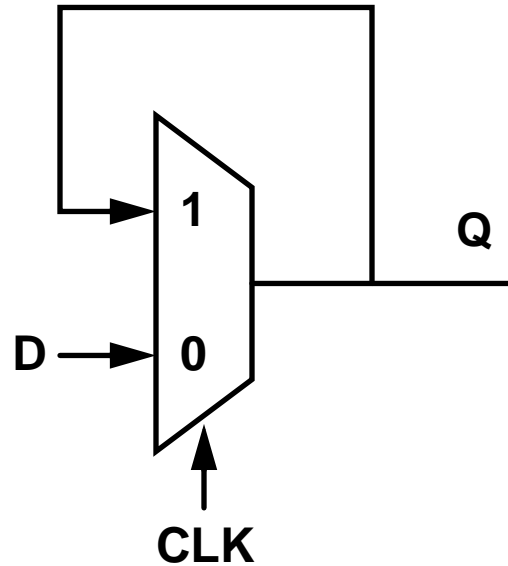
Question: how do we **write** a new value?

- Cutting feedback loop (multiplexer-based)
- Overpowering feedback loop

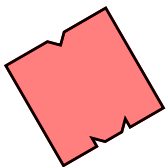
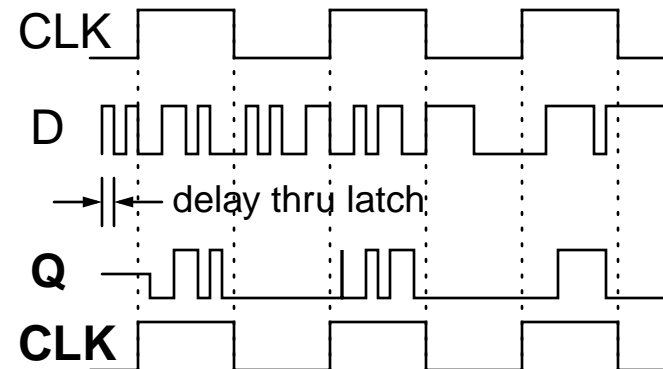
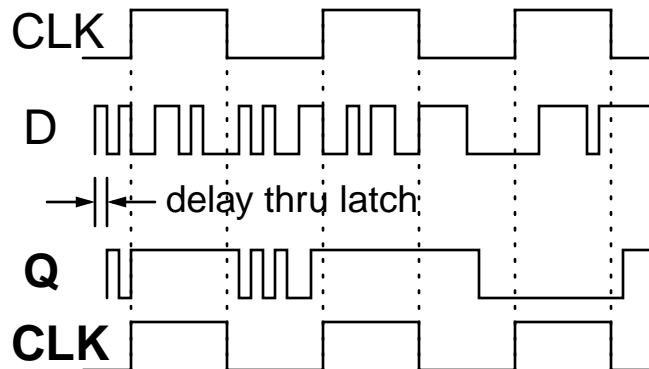
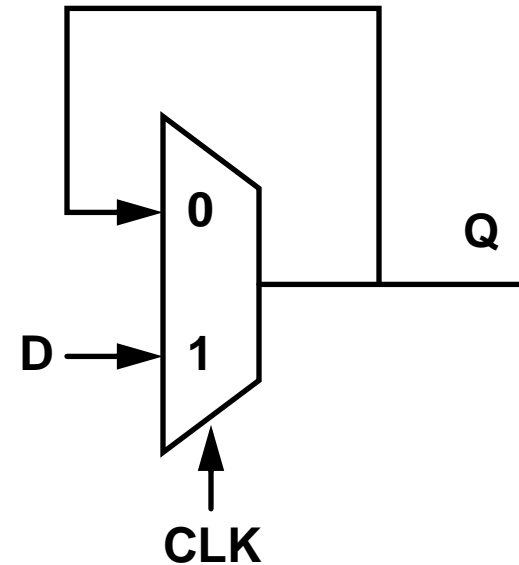


Multiplexer-Based Latches

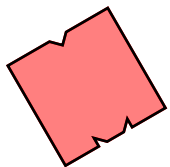
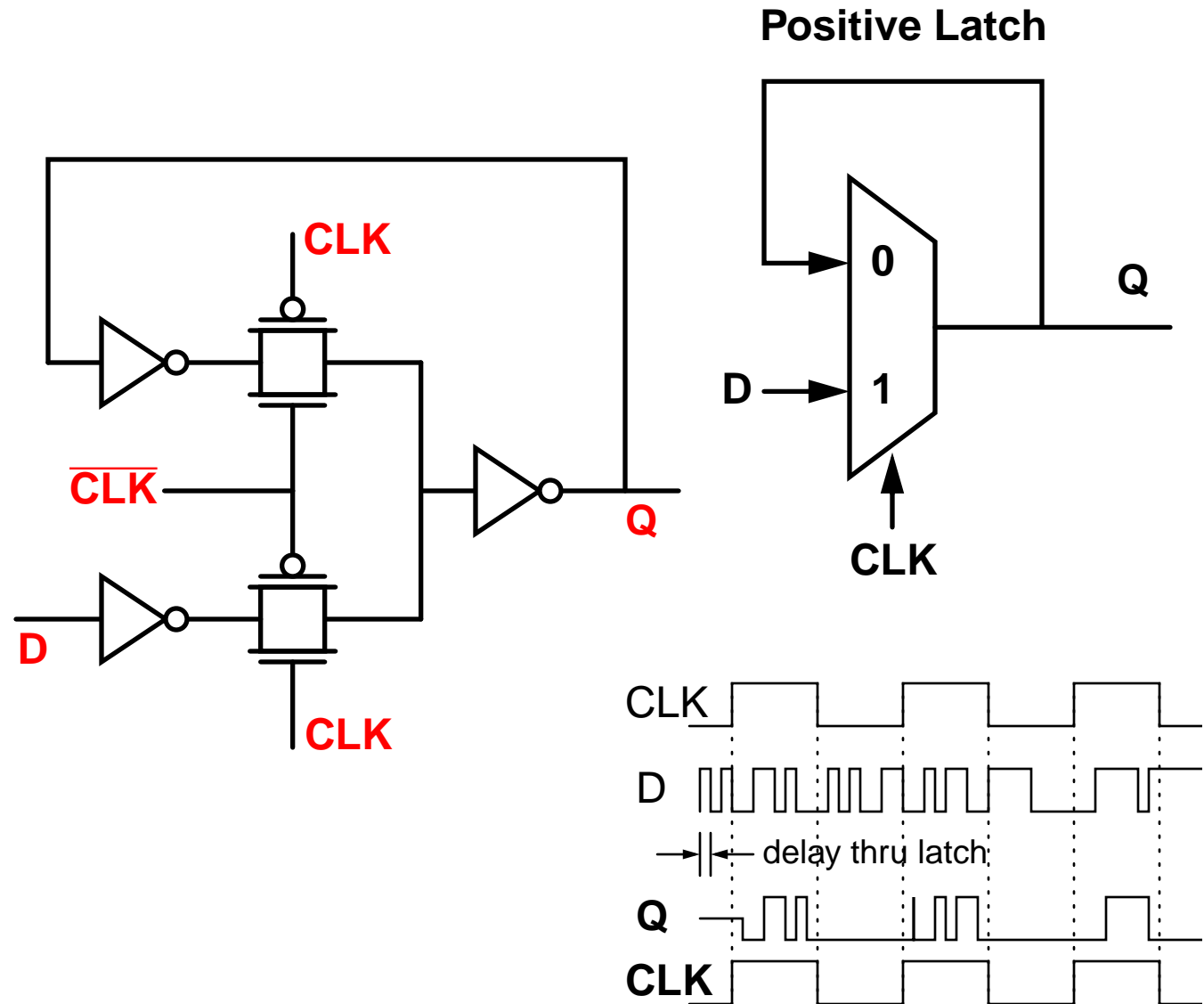
Negative Latch



Positive Latch

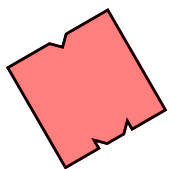
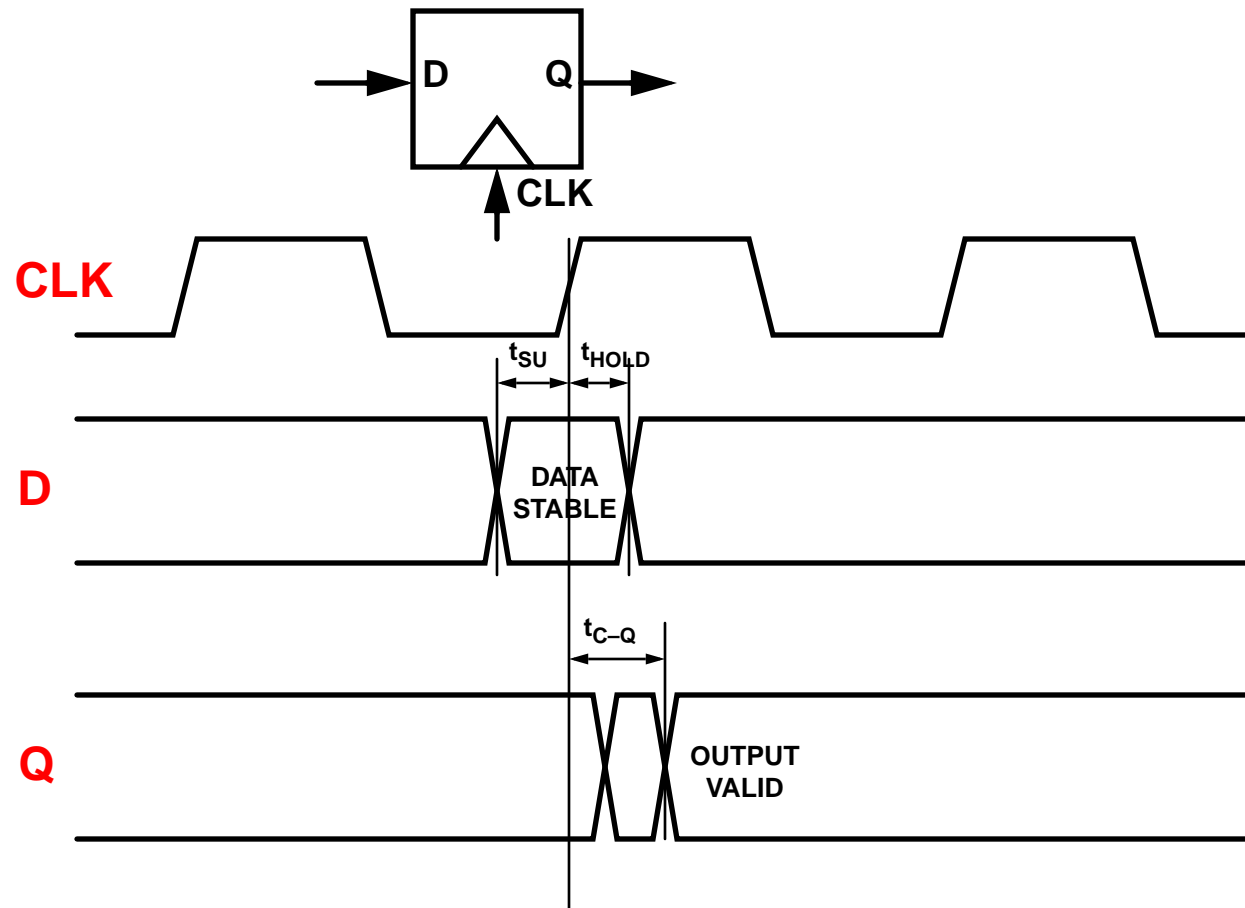


Multiplexer-Based Latches



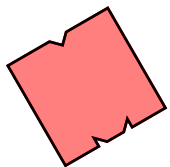
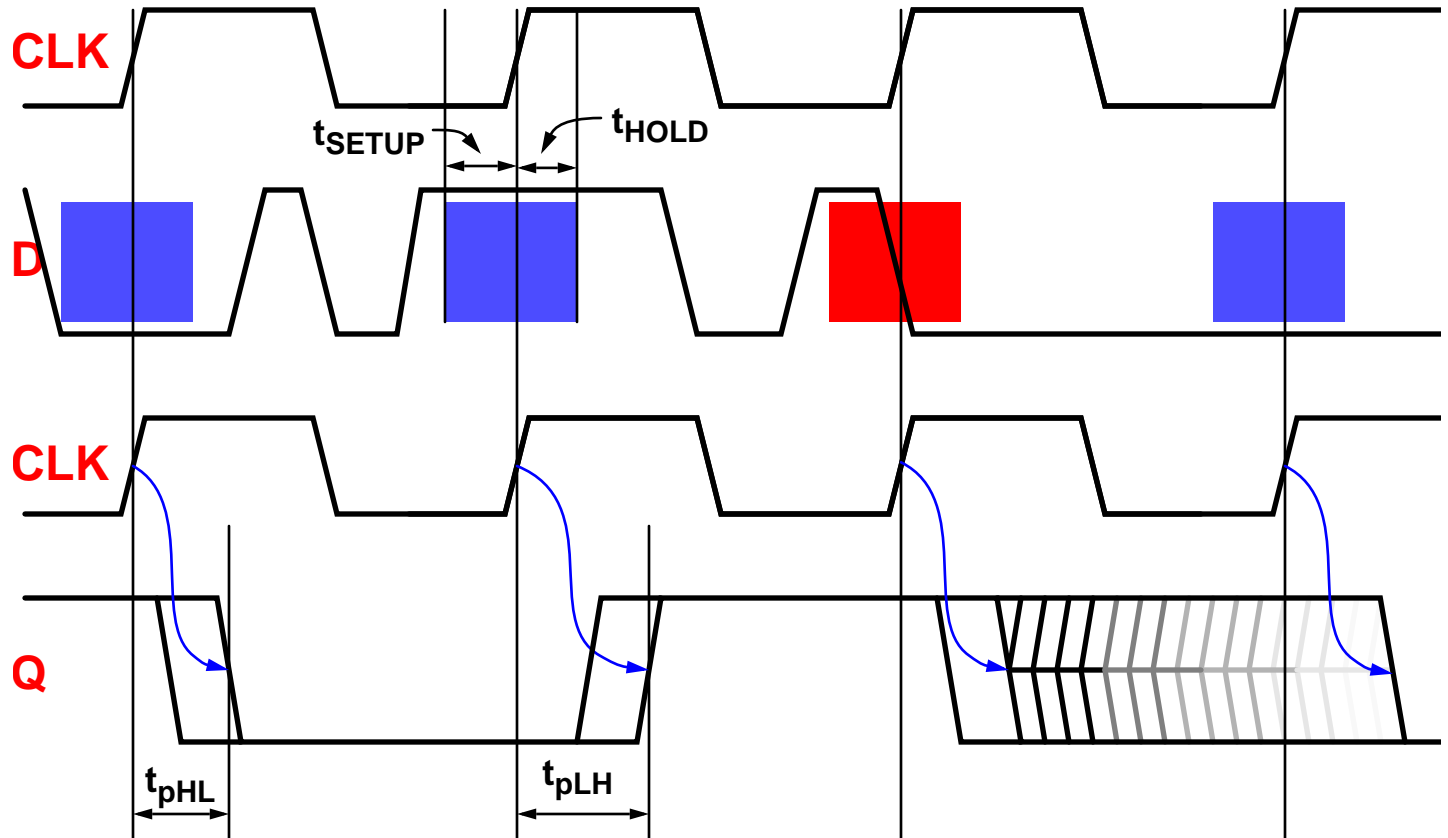
Metastability

SET-UP and HOLD times



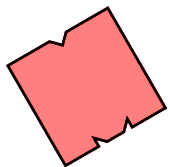
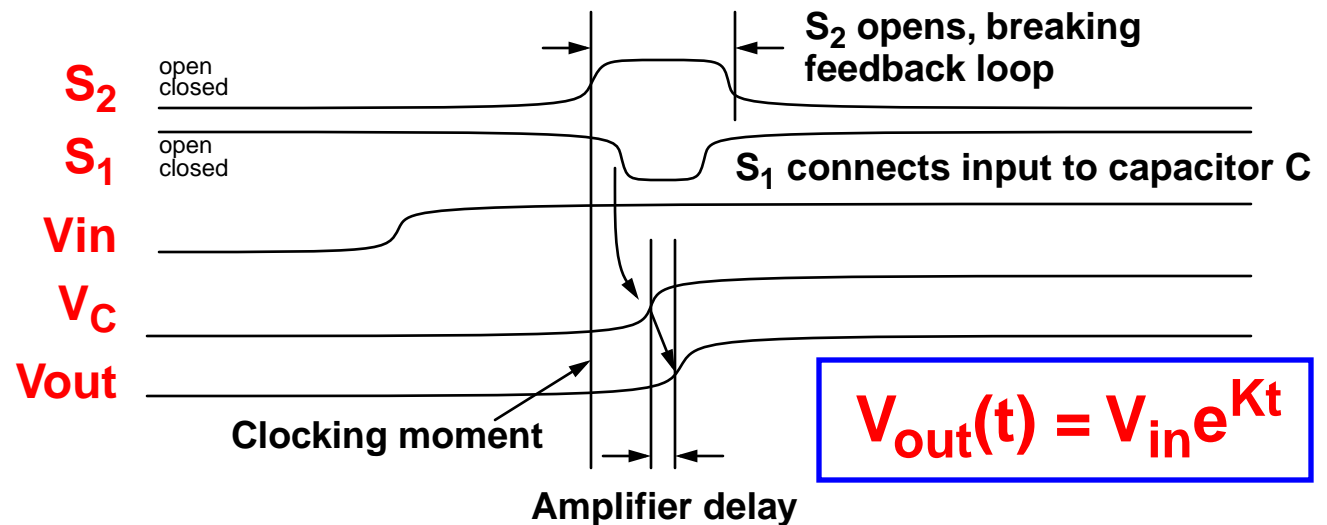
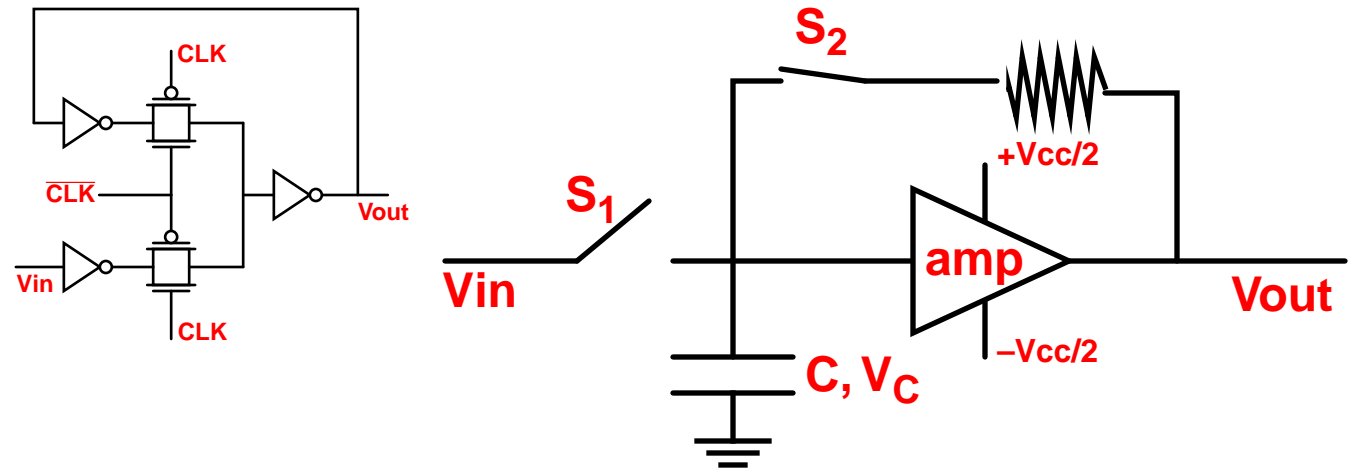
Metastability

SET-UP and HOLD time violations



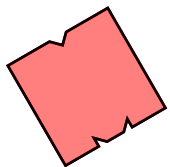
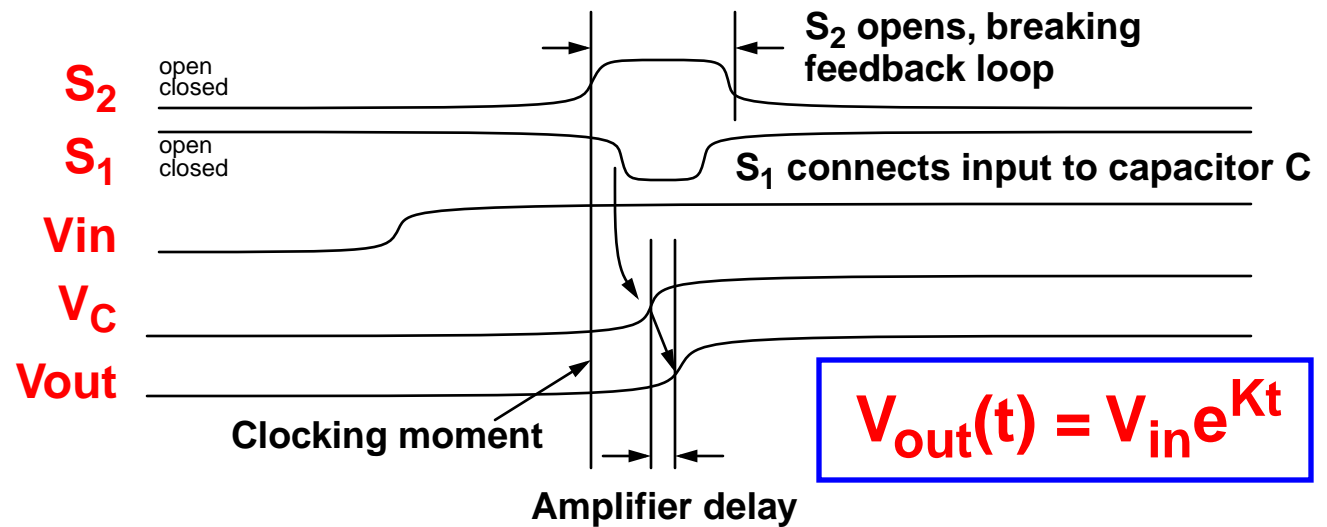
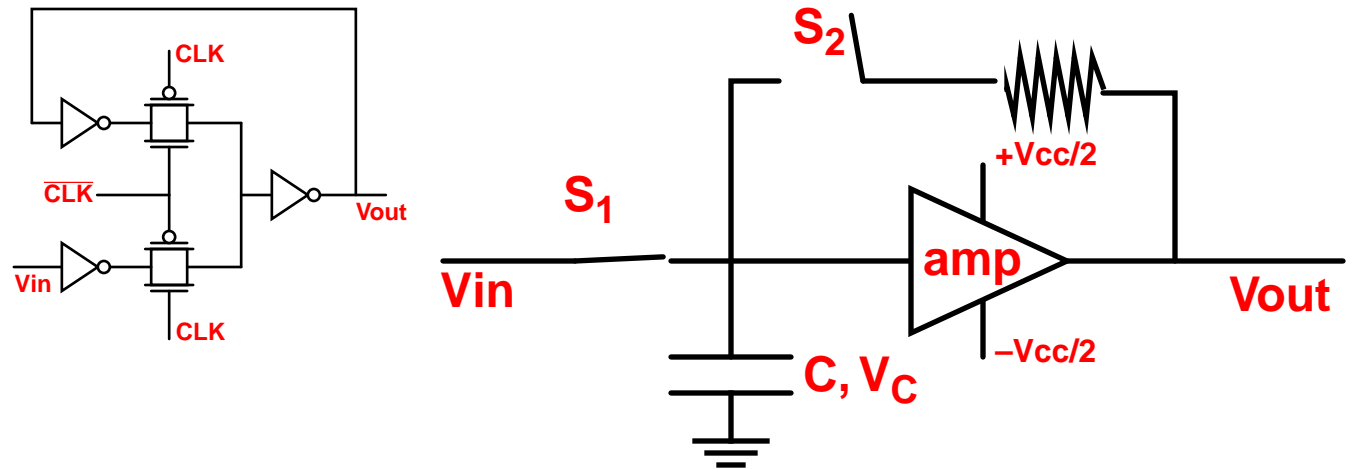
Metastability

Intuition behind the behavior



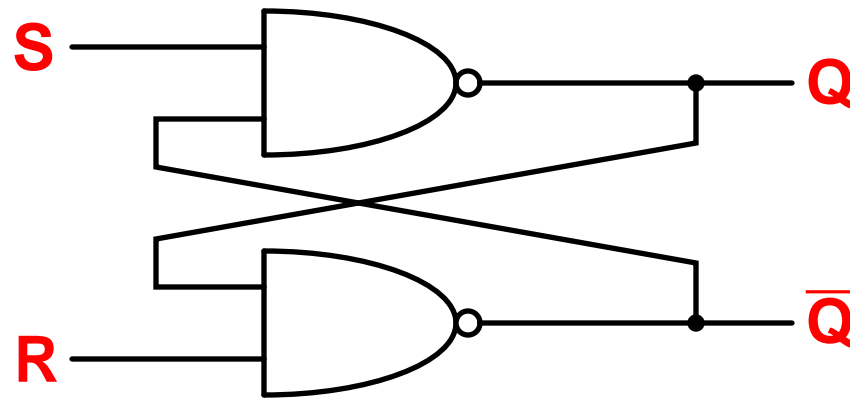
Metastability

Intuition behind the behavior

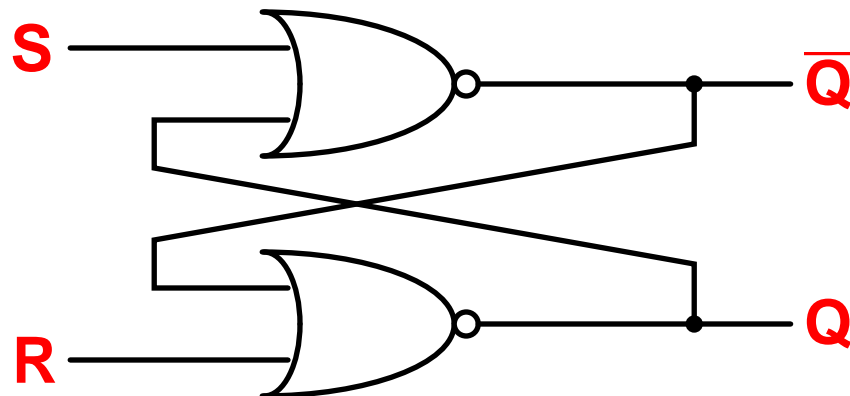


Static latches & registers

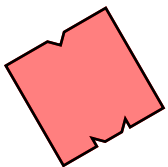
Set-Reset Flip-Flop (two types)



S	R	Q	\bar{Q}
0	0	1	1
1	0	0	1
0	1	1	0
1	1	Q	\bar{Q}

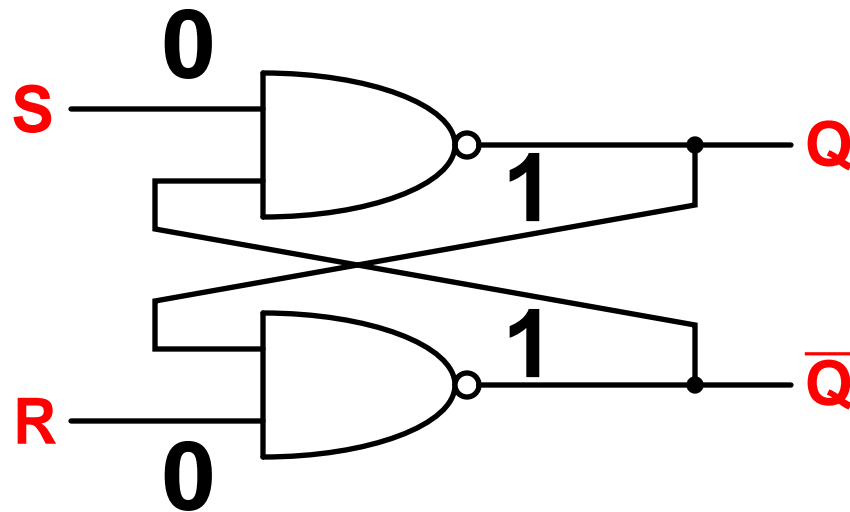


S	R	Q	\bar{Q}
0	0	Q	\bar{Q}
1	0	1	0
0	1	0	1
1	1	0	0



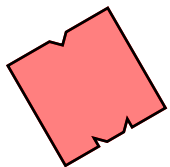
Static latches & registers

NAND-based SR Flip-Flop



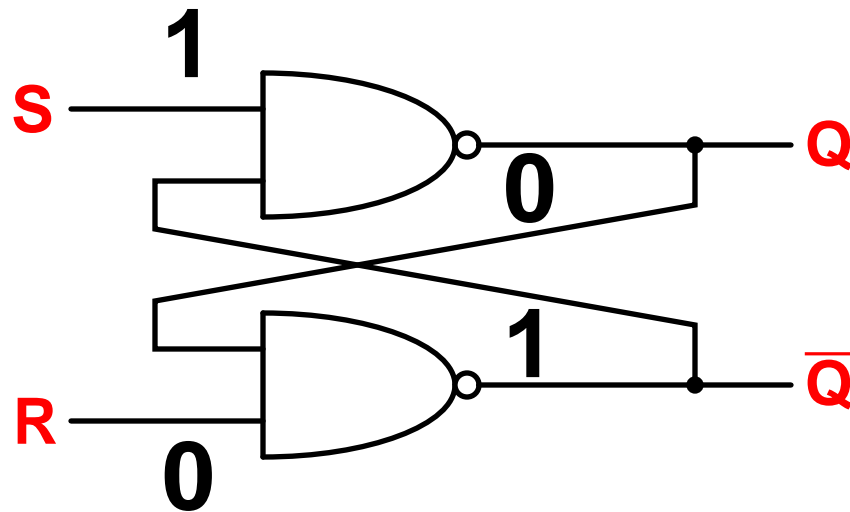
S	R	Q	\bar{Q}
0	0	1	1
1	0	0	1
0	1	1	0
1	1	Q	\bar{Q}

“forbidden” state, $Q == \bar{Q}$

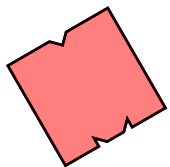


Static latches & registers

NAND-based SR Flip-Flop

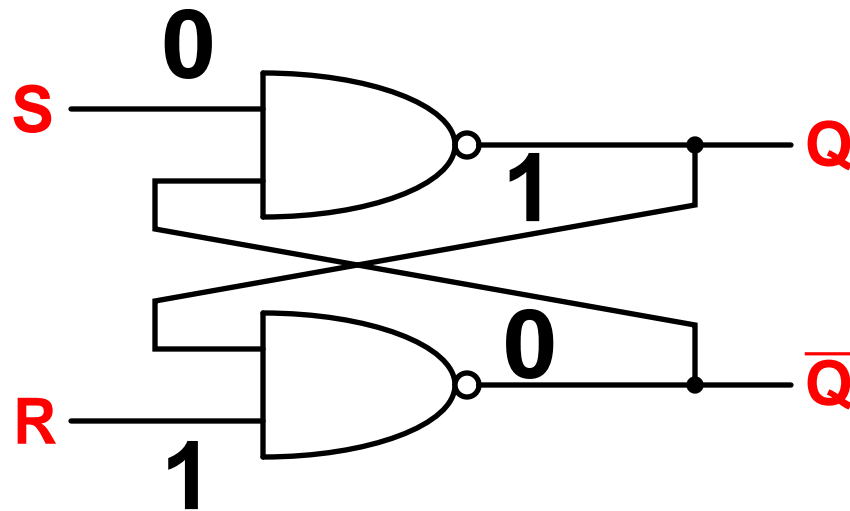


S	R	Q	\bar{Q}
0	0	1	1
1	0	0	1
0	1	1	0
1	1	Q	\bar{Q}

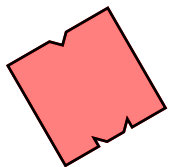


Static latches & registers

NAND-based SR Flip-Flop

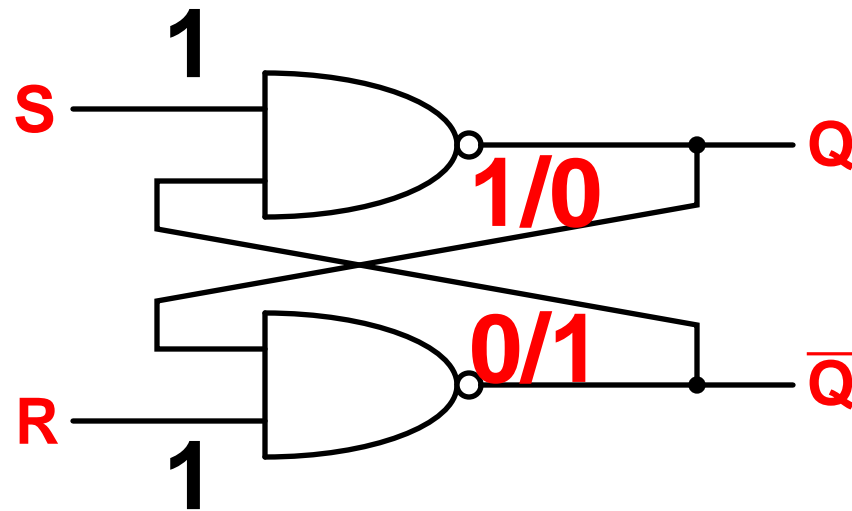


S	R	Q	\bar{Q}
0	0	1	1
1	0	0	1
0	1	1	0
1	1	Q	\bar{Q}



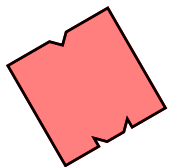
Static latches & registers

NAND-based SR Flip-Flop



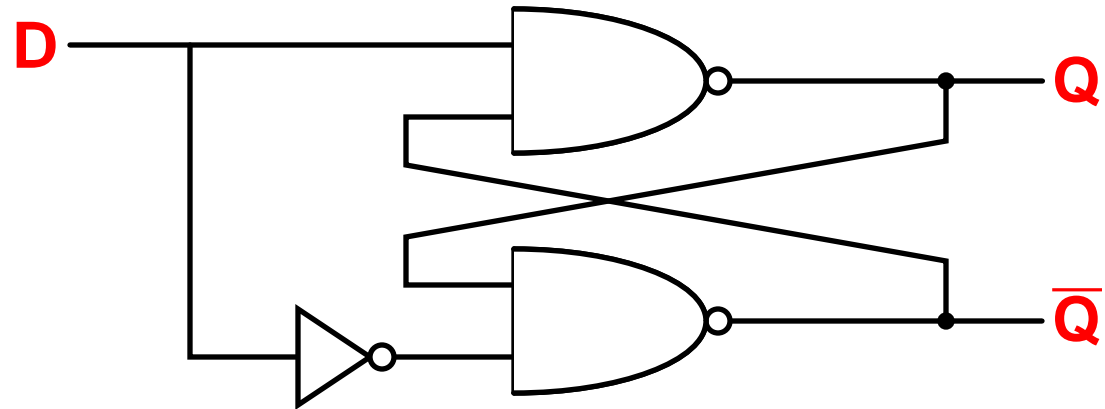
S	R	Q	\bar{Q}
0	0	1	1
1	0	0	1
0	1	1	0
1	1	Q	\bar{Q}

Q and \bar{Q} keep their previous values if this state is reached from a non-forbidden state



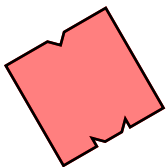
Some Issues

Forbidden FF states



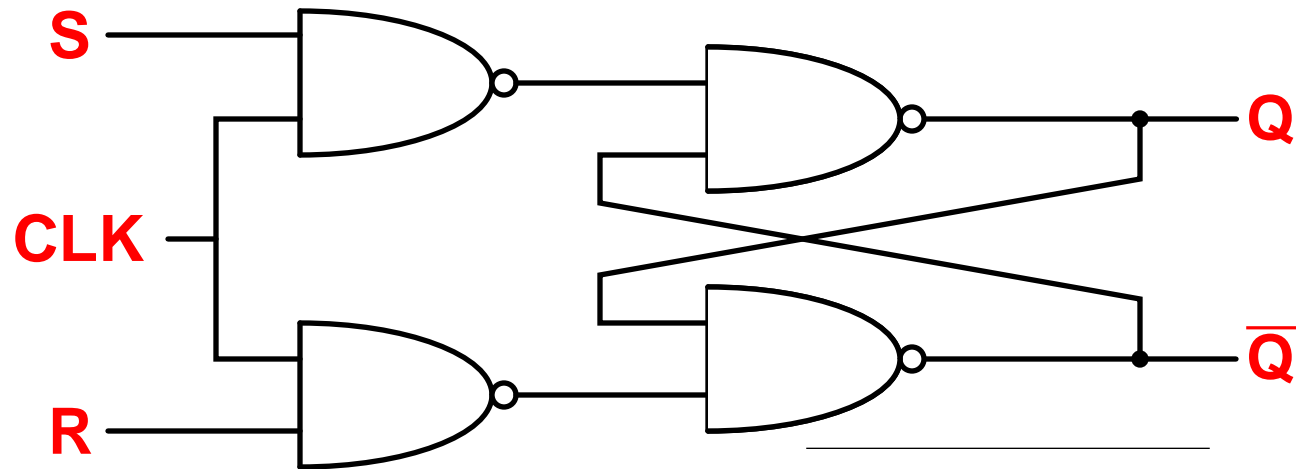
D	Q_{t+1}
1	0
0	1

**D latch
(transparent)**



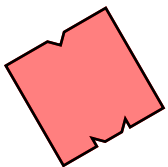
Some Issues

Forbidden FF states



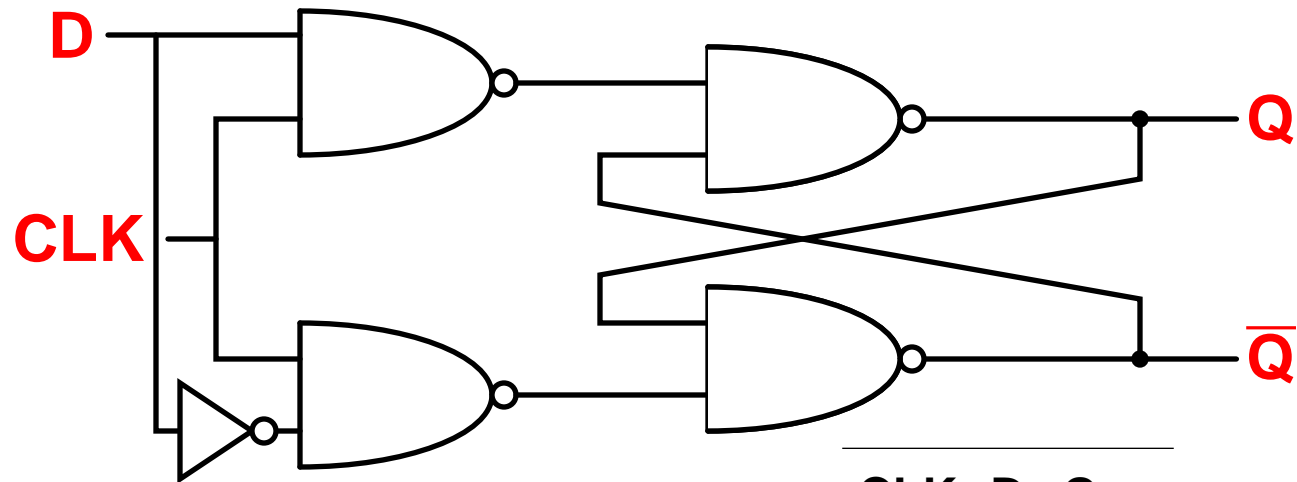
**Gated SR latch
(transparent)**

CLK	S	R	Q_{t+1}
0	x	x	Q_t
1	0	0	Q_t
1	0	1	0
1	1	0	1
1	1	1	x



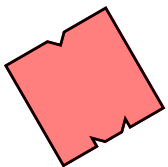
Some Issues

Forbidden FF states



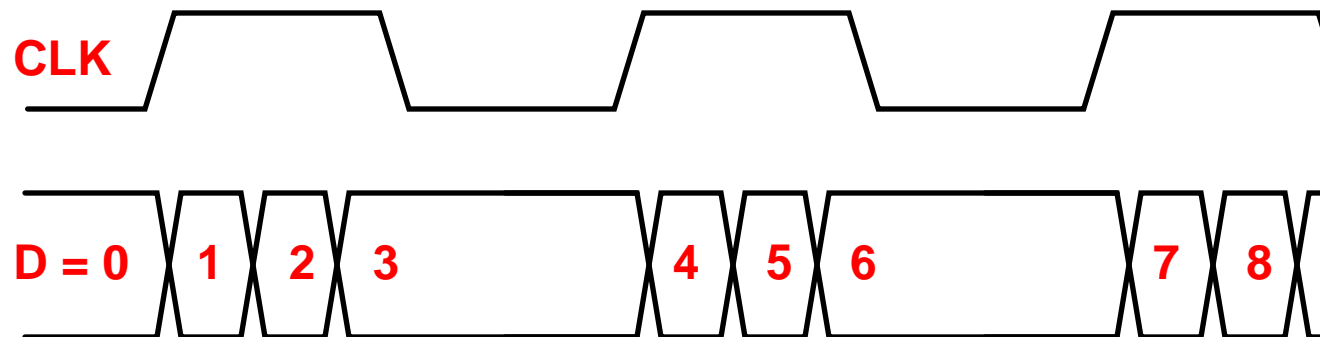
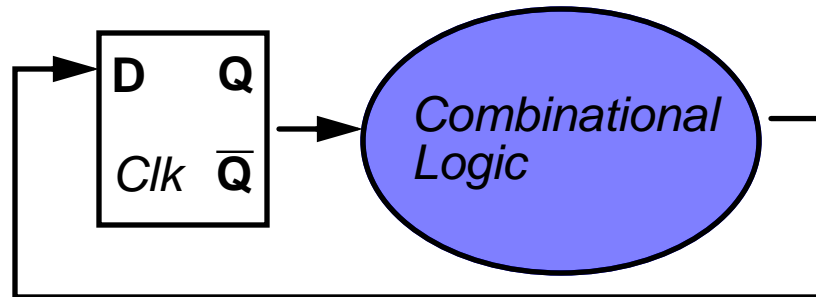
**Gated D-latch
(transparent)**

CLK	D	Q_{t+1}
0	x	Q_t
1	0	0
1	1	1

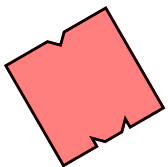


Some Issues

Feed-through and race conditions

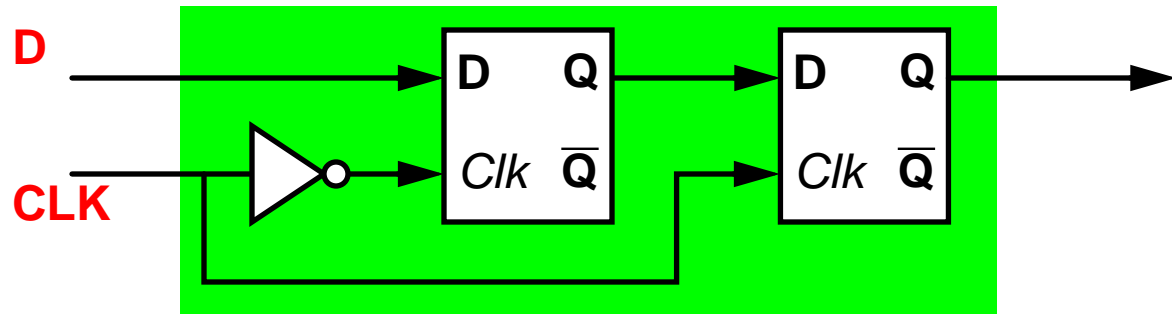


Transparent latches allow combinational logic *results* to be seen as its own *inputs*

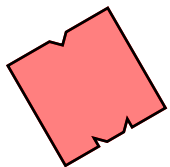
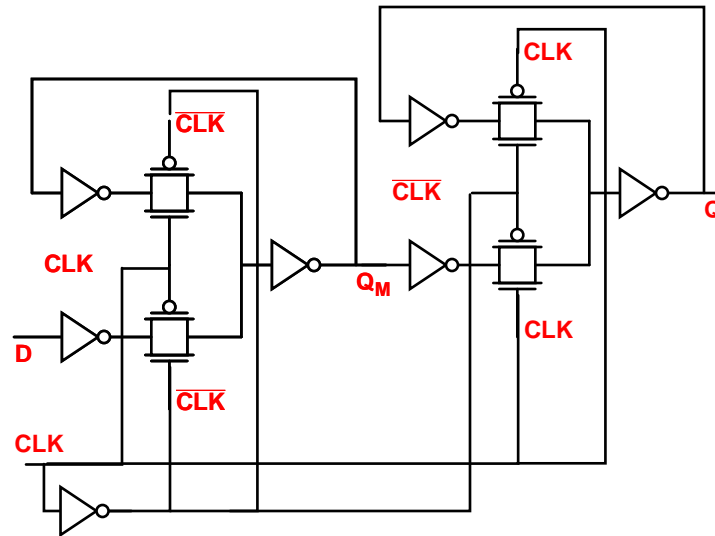


Some Issues

Feed-through and race conditions

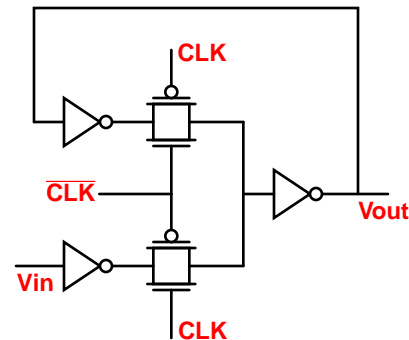


Master-slave D register (neg-edge triggered)



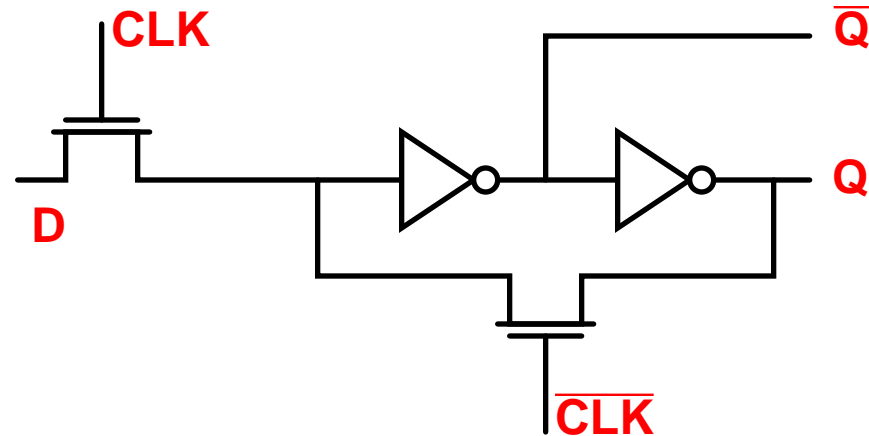
Some Issues

Cost of Clock Network (driving huge load)

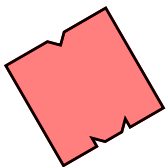


Clock network drives 4 transistors per latch ... power-expensive.

Alternative design:

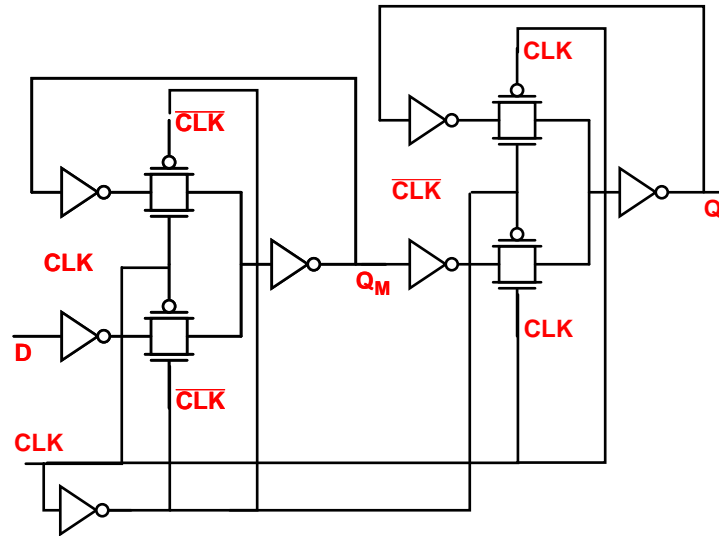


- Design w/ NMOS pass transistors presents smaller load to CLK; INV can recover low "1" but at a cost
- However: requires non-overlapping CLK/ $\overline{\text{CLK}}$... why?

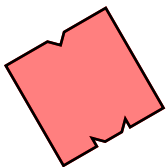
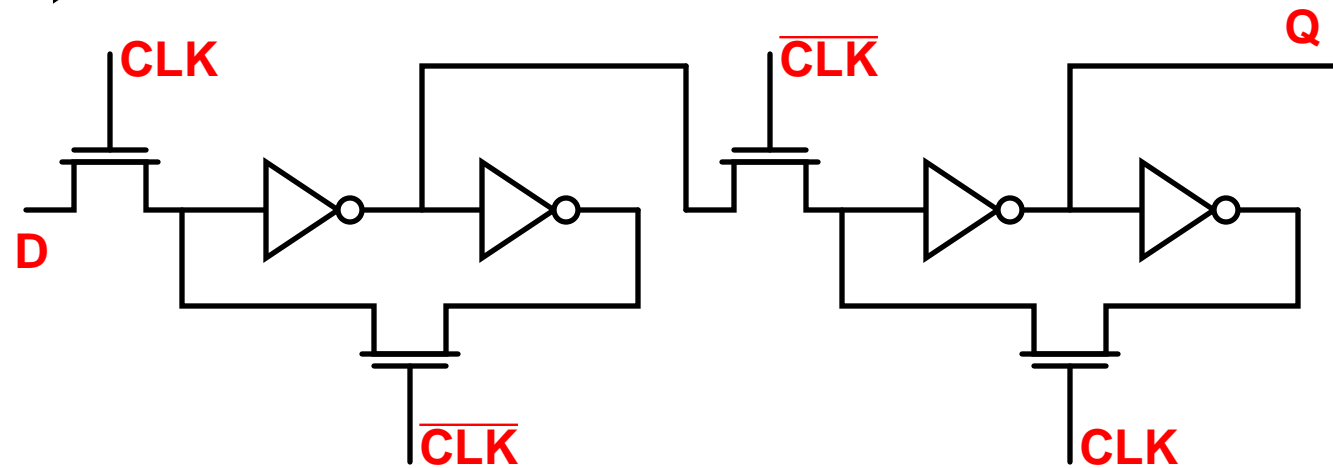


Some Issues

Cost of Clock Network (driving huge load)



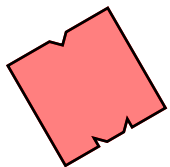
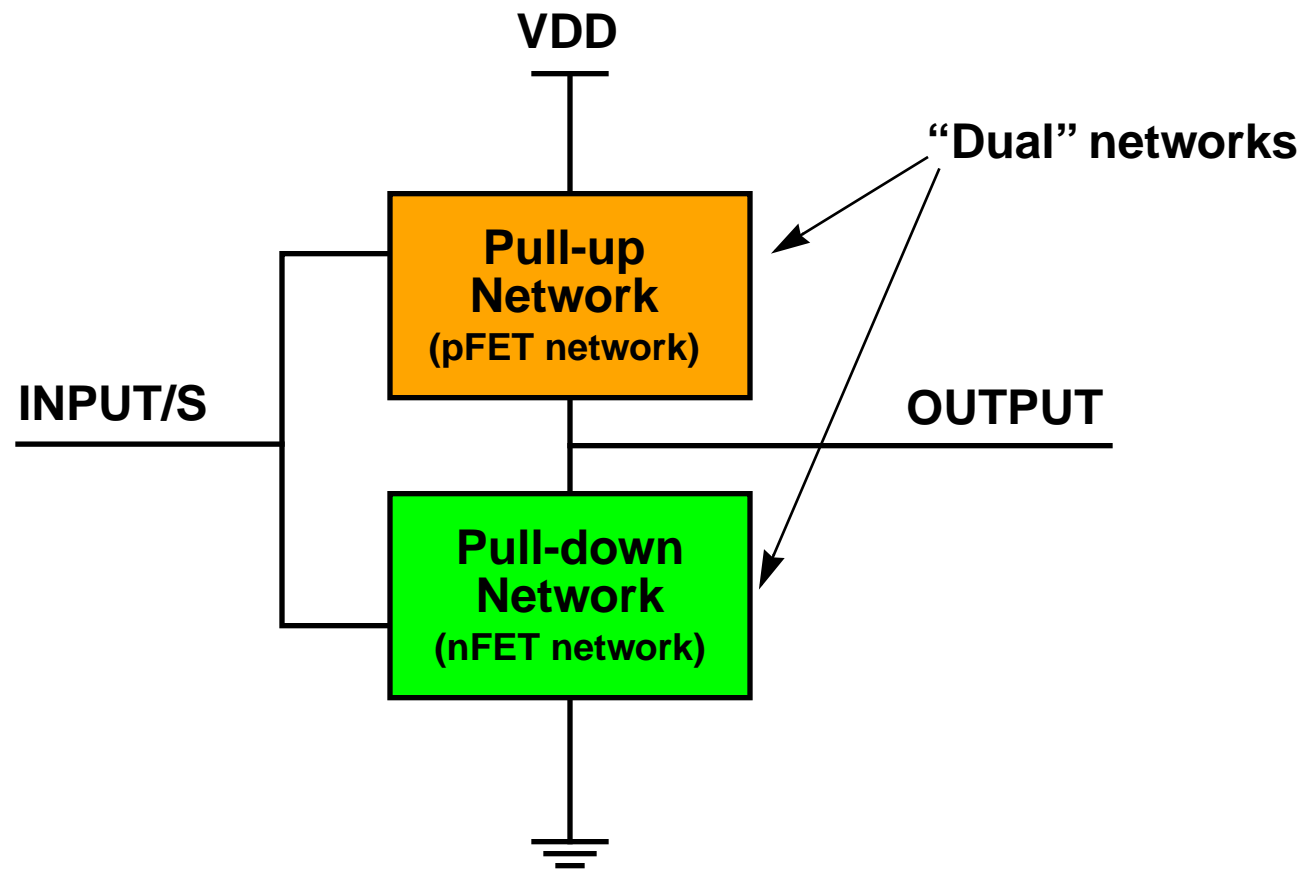
Similar example,
with master-slave
organization



Some Issues

Number of Transistors: Dynamic Logic

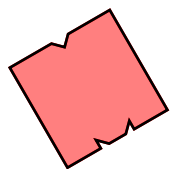
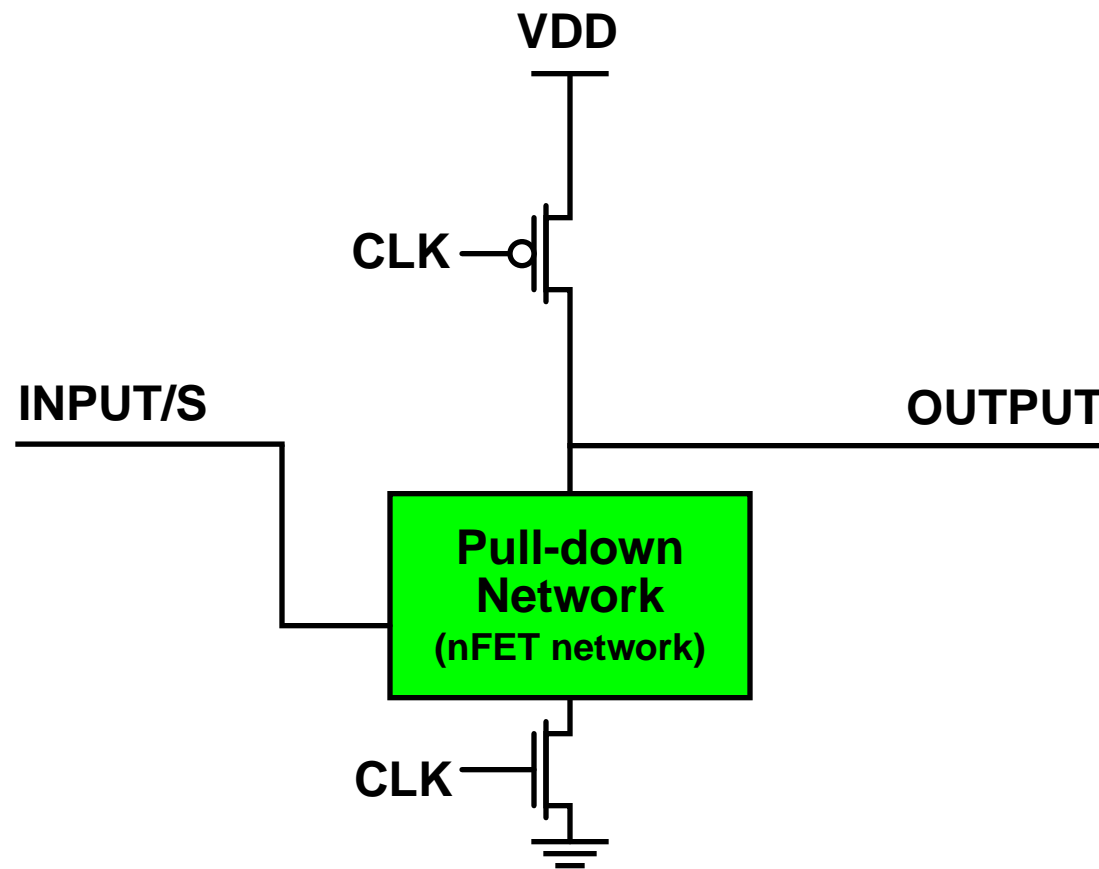
(first: Primer ... recall complementary logic)



Some Issues

Number of Transistors: Dynamic Logic

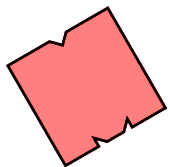
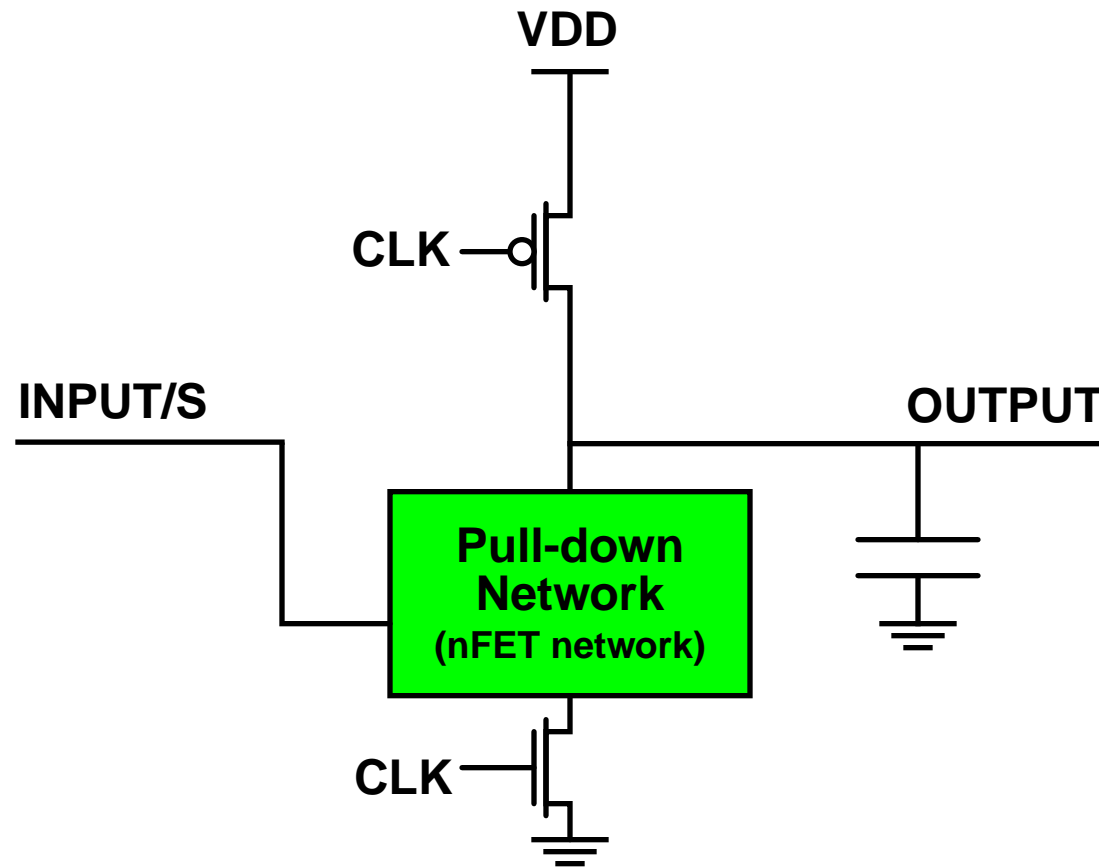
(... no longer complementary ...)



Some Issues

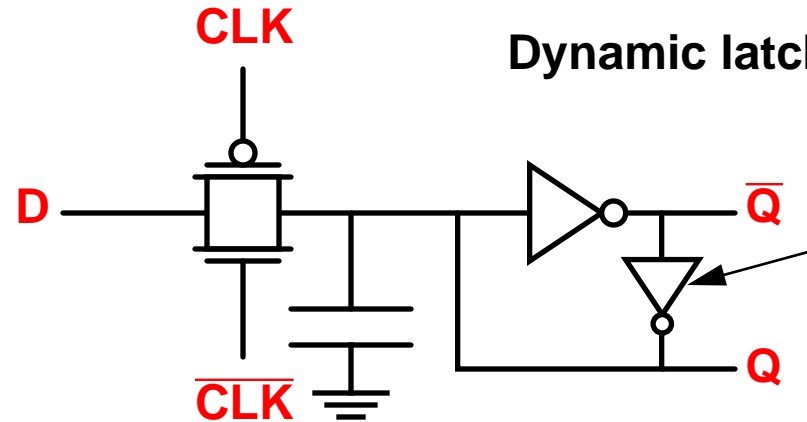
Number of Transistors: Dynamic Logic

(... relies upon capacitance, burns power)



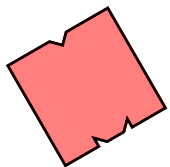
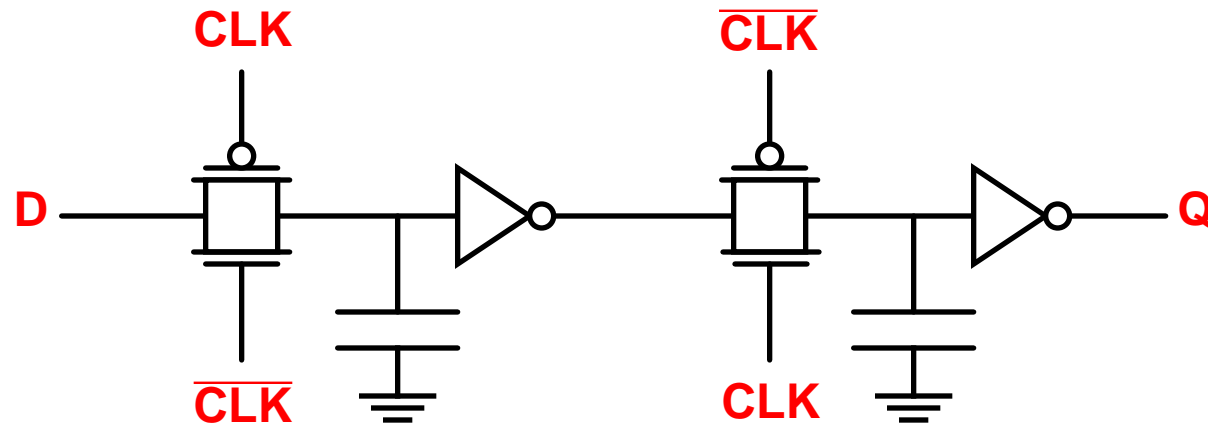
Some Issues

Number of Transistors: *Dynamic* Storage



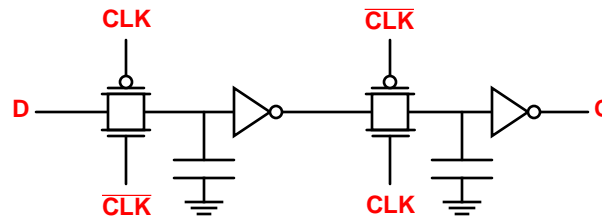
Create “pseudostatic” latch:
Make this inverter weak
so that D input overpowers
feedback loop.
How to make weak inverter:
W/L: make W small or L large

Dynamic edge-triggered register



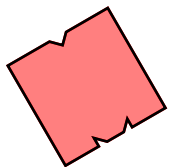
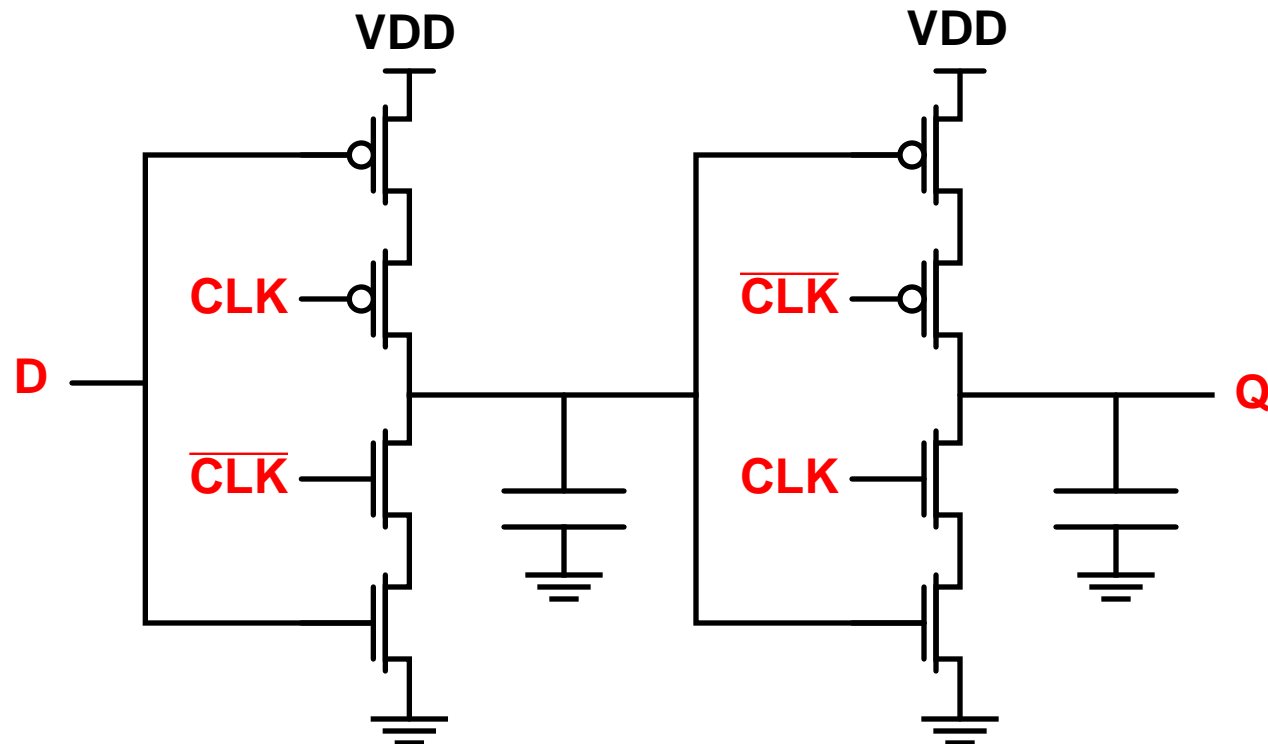
Some Issues

Non-overlapping clocks: Clocked CMOS



This allows feed-through when clocks overlap.

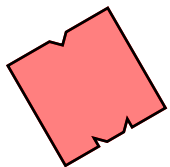
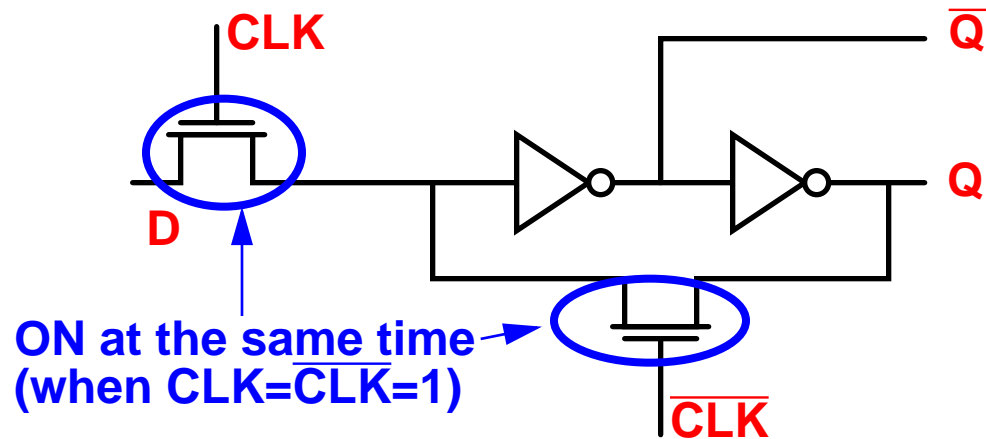
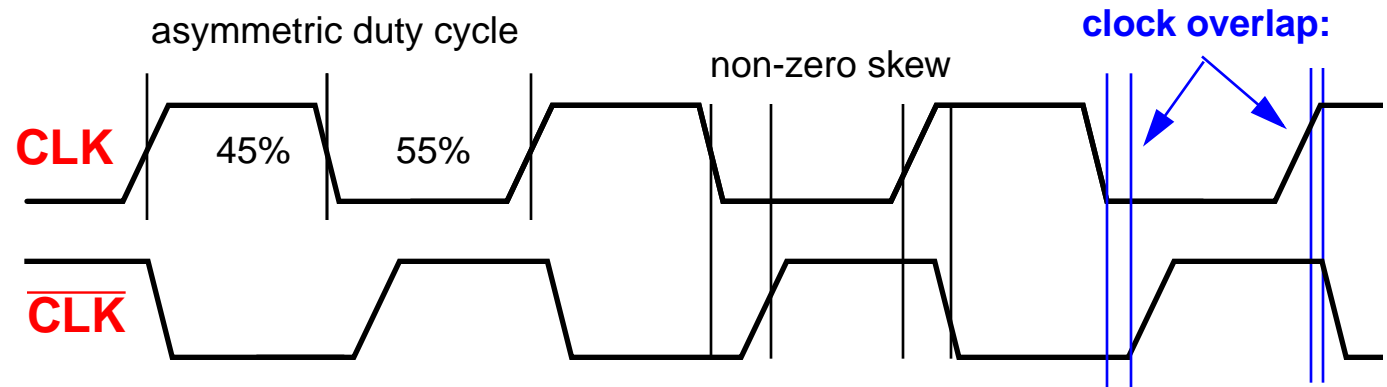
This design does not:



Some Issues

Non-overlapping clocks: Clocked CMOS

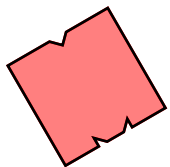
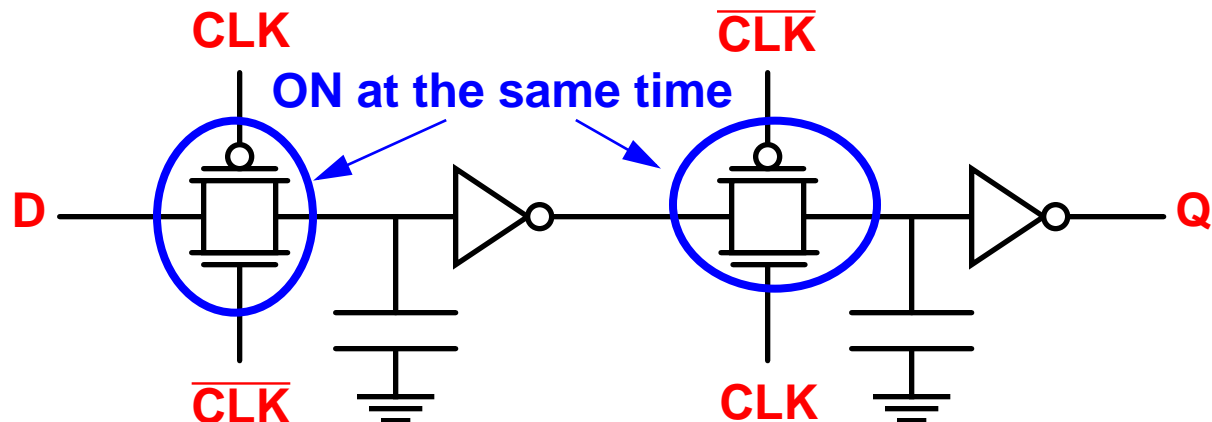
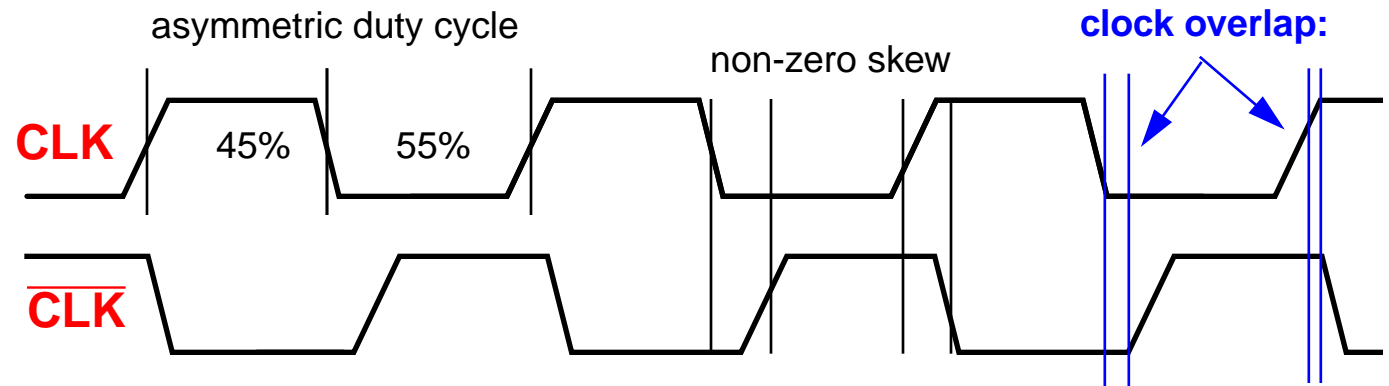
EXAMPLES:



Some Issues

Non-overlapping clocks: Clocked CMOS

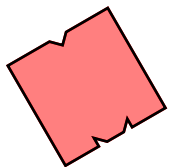
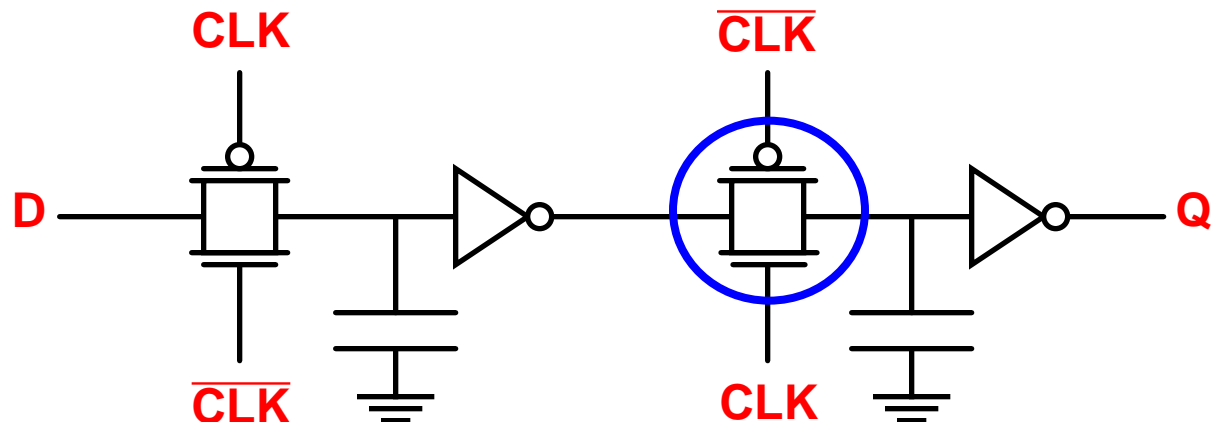
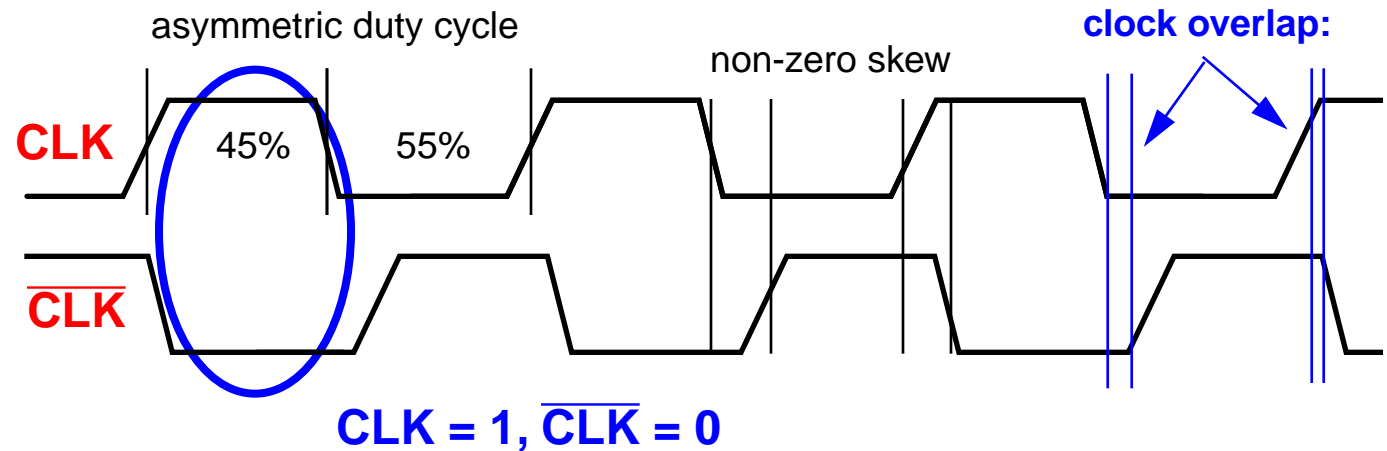
EXAMPLES:



Some Issues

Non-overlapping clocks: Clocked CMOS

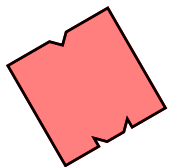
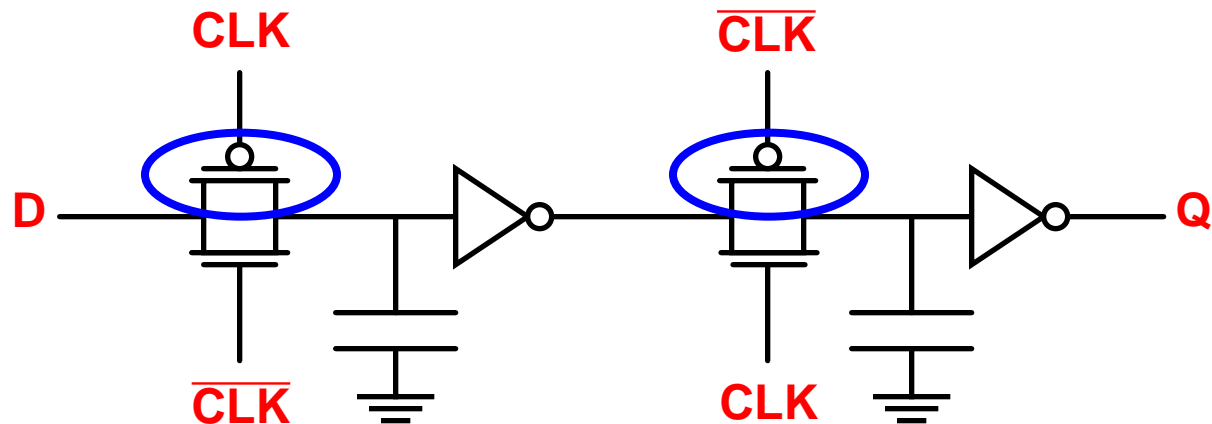
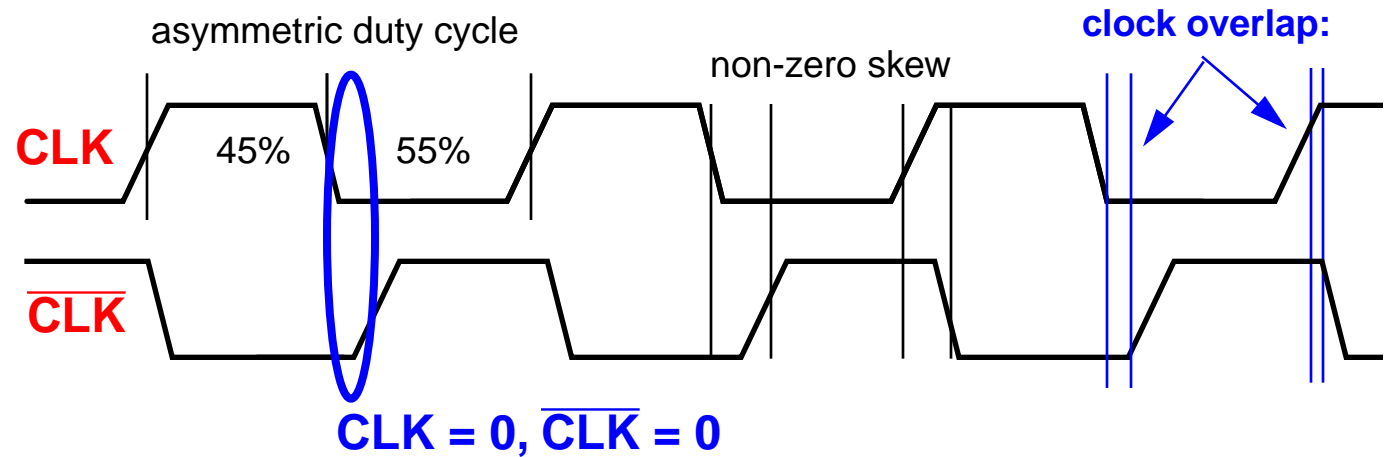
EXAMPLES:



Some Issues

Non-overlapping clocks: Clocked CMOS

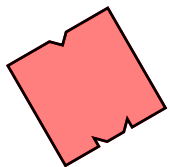
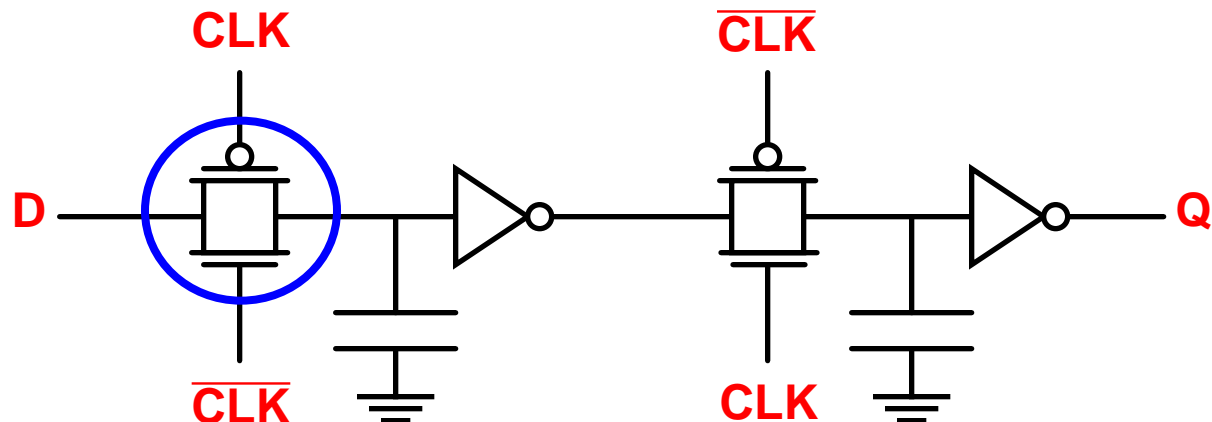
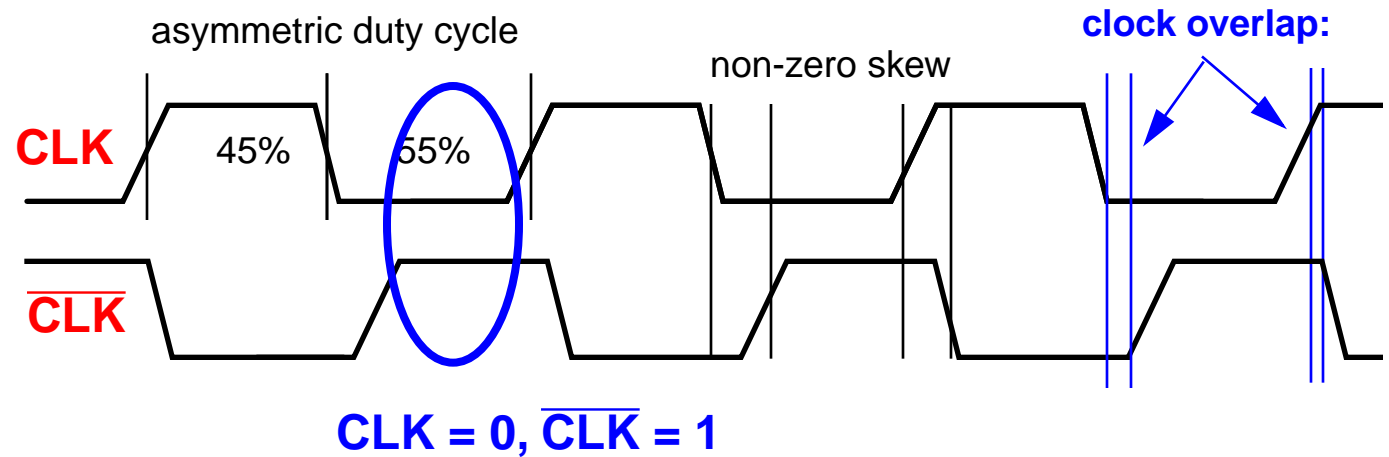
EXAMPLES:



Some Issues

Non-overlapping clocks: Clocked CMOS

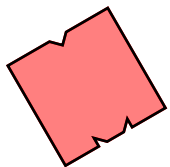
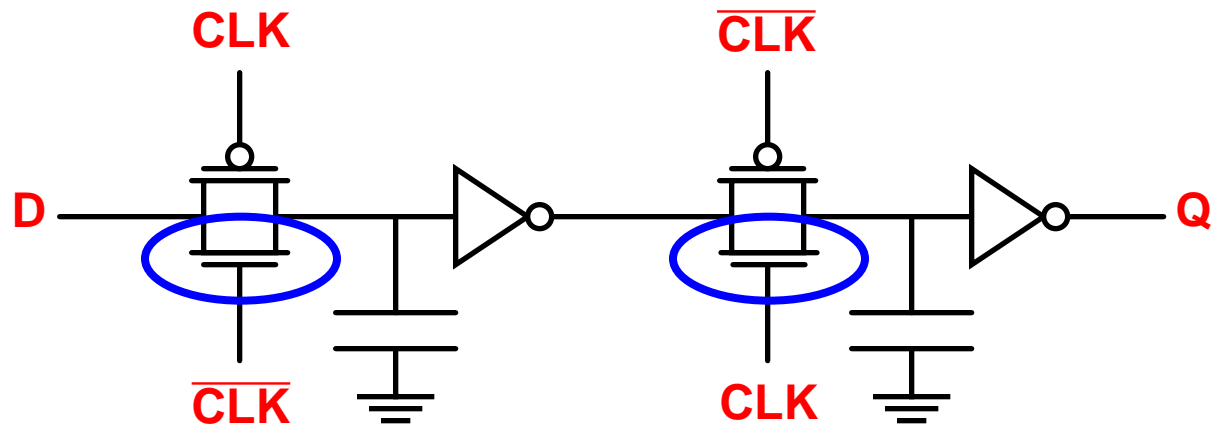
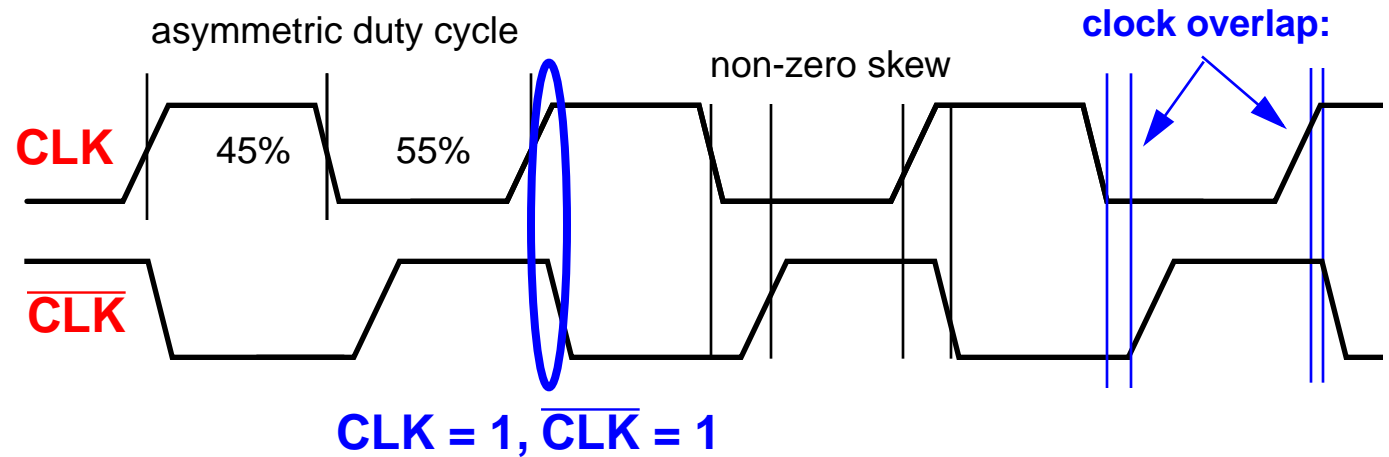
EXAMPLES:



Some Issues

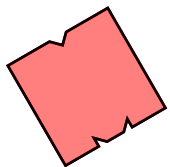
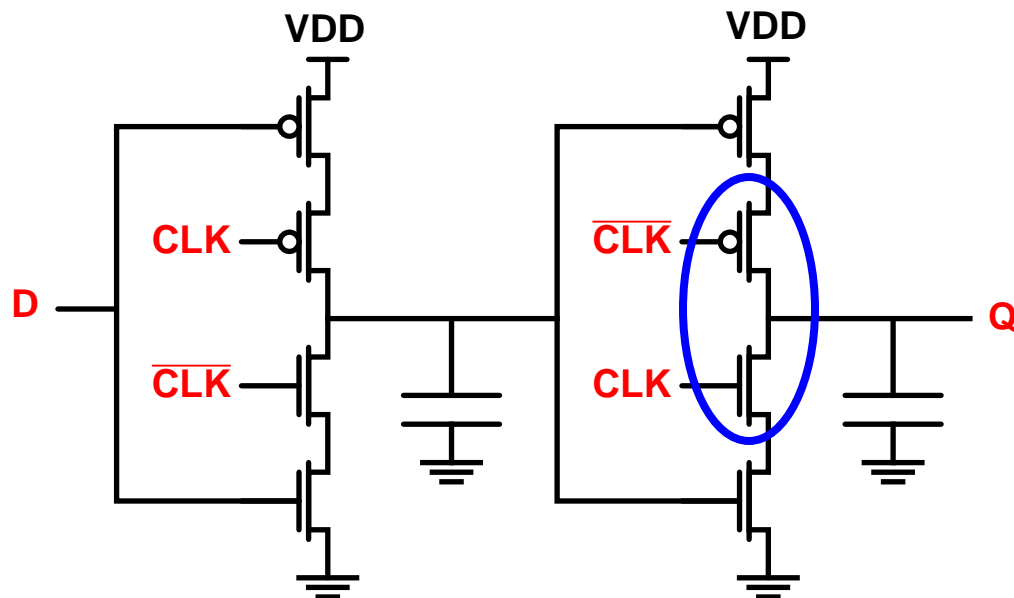
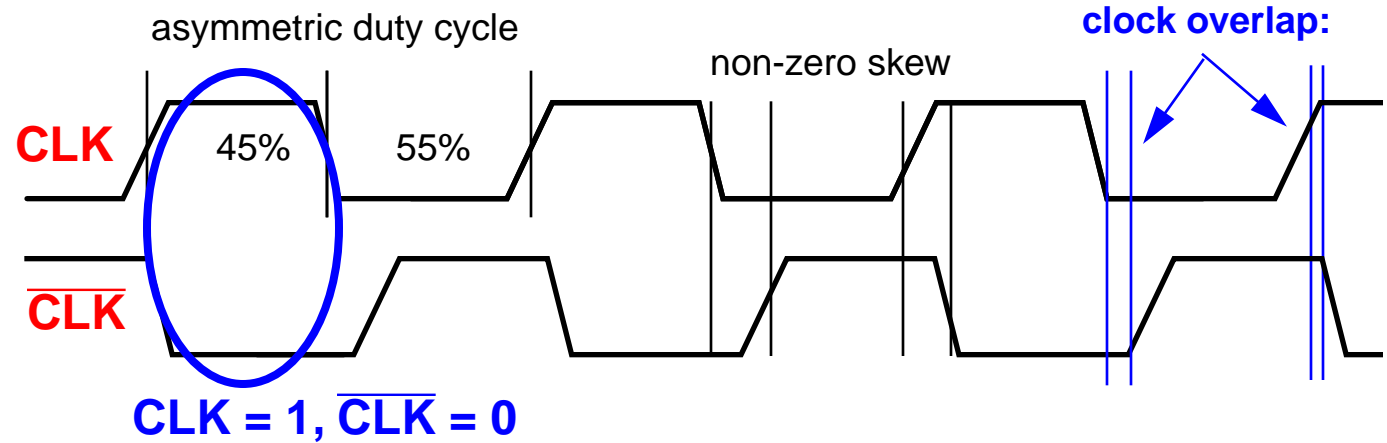
Non-overlapping clocks: Clocked CMOS

EXAMPLES:



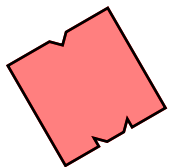
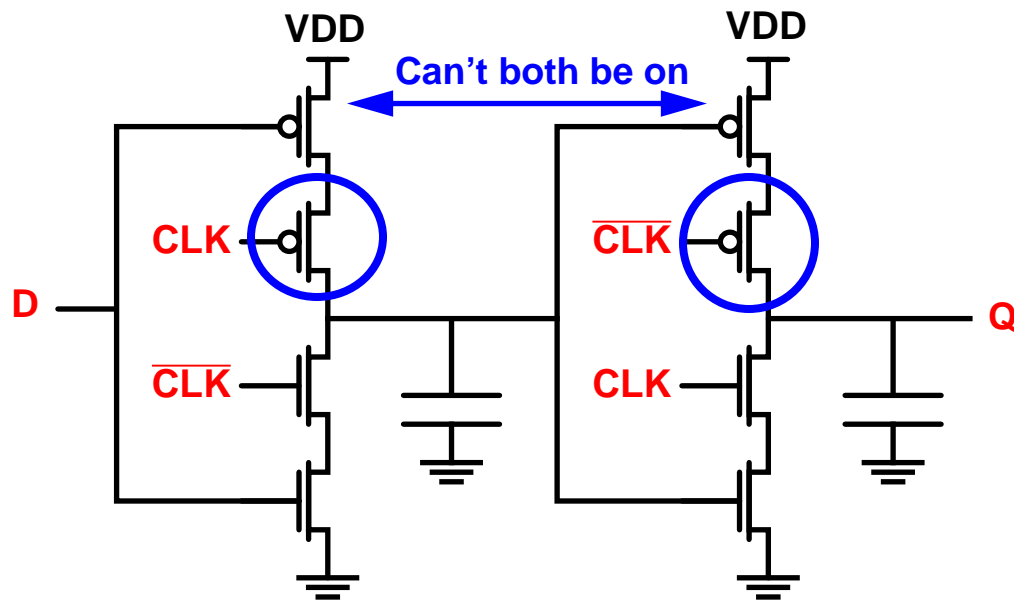
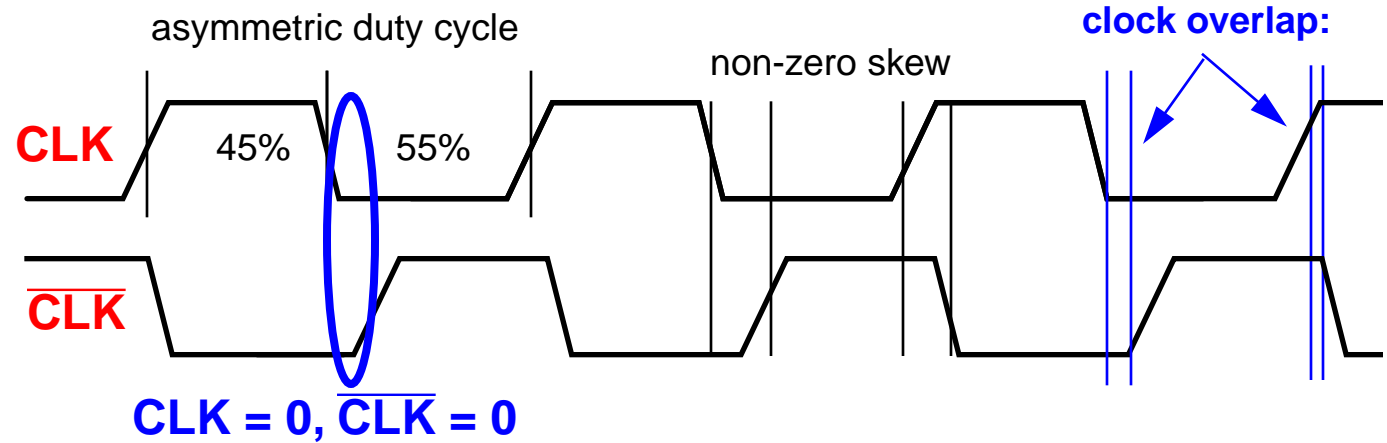
Some Issues

Non-overlapping clocks: Clocked CMOS



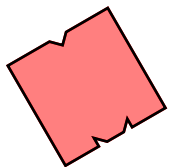
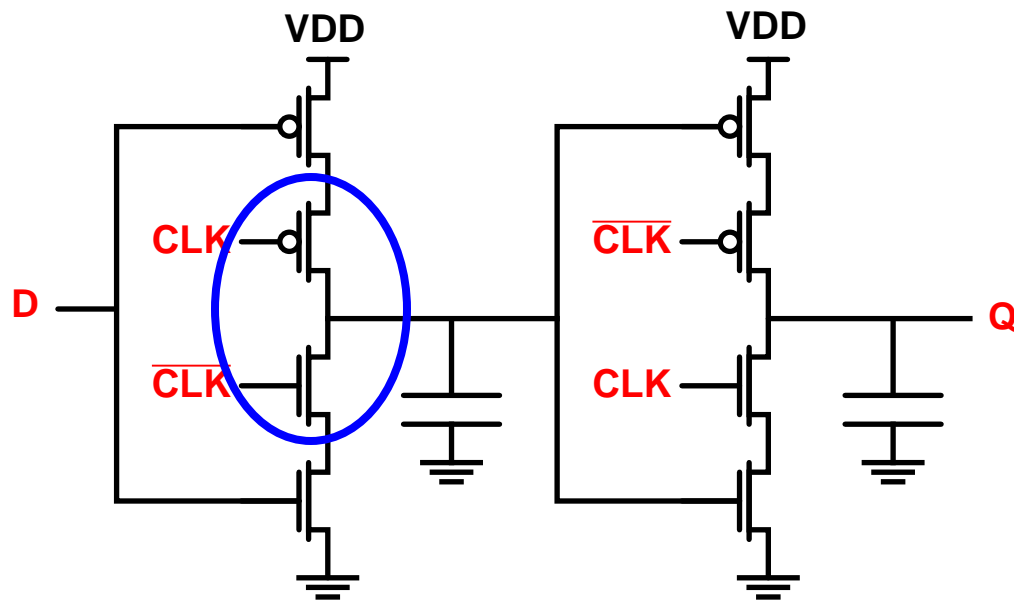
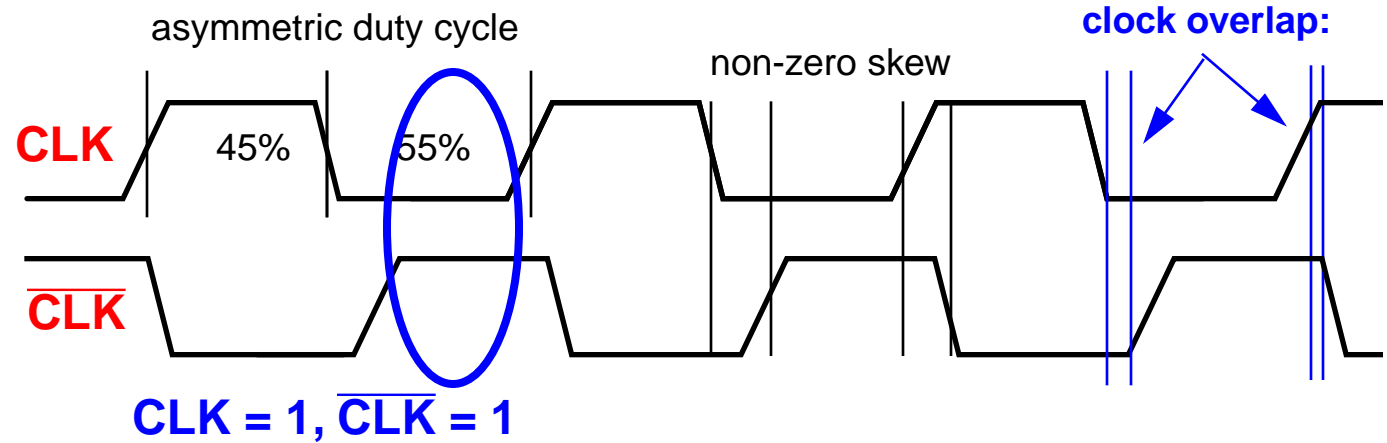
Some Issues

Non-overlapping clocks: Clocked CMOS



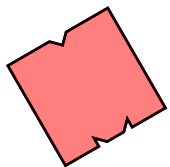
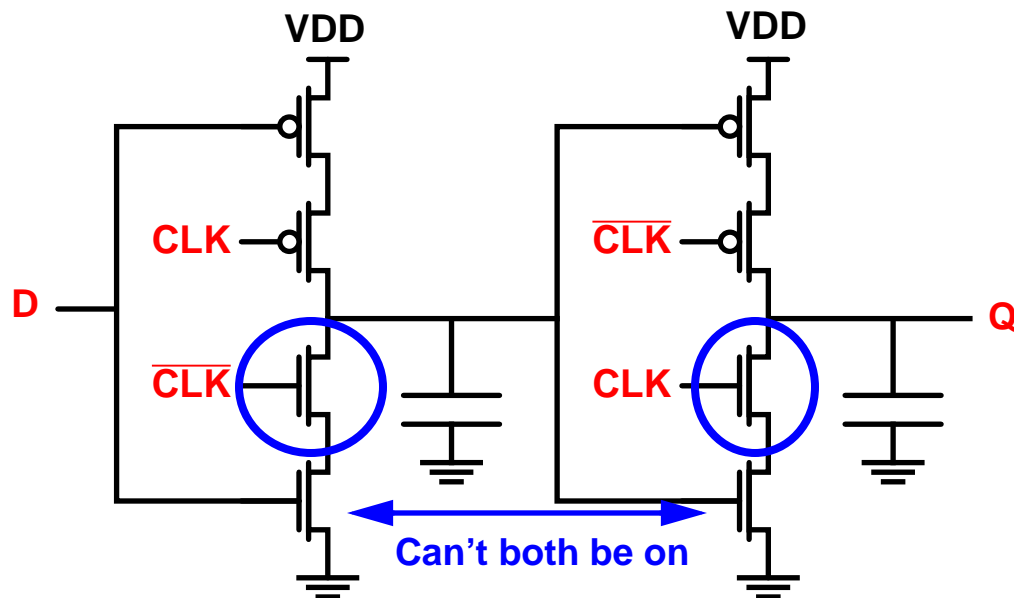
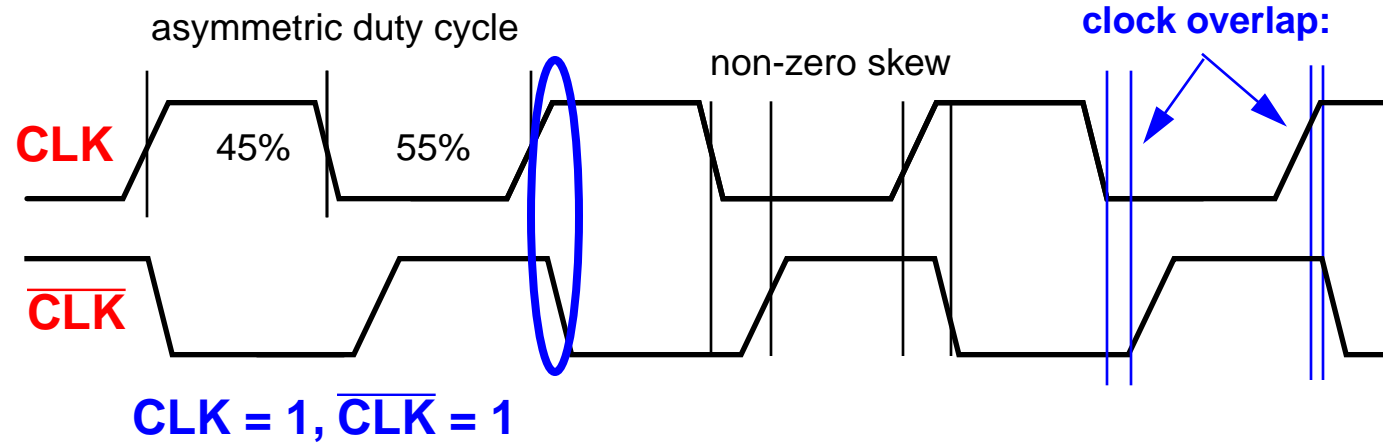
Some Issues

Non-overlapping clocks: Clocked CMOS



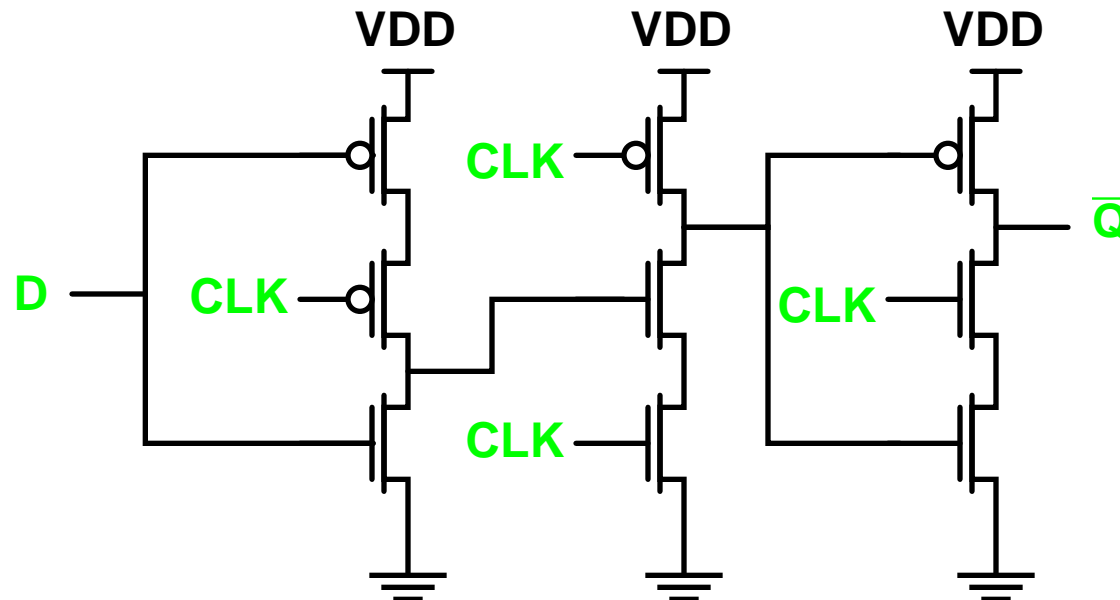
Some Issues

Non-overlapping clocks: Clocked CMOS

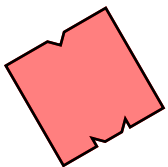


Some Issues

Non-overlapping clocks: “True” Single-Phase Clocked Register

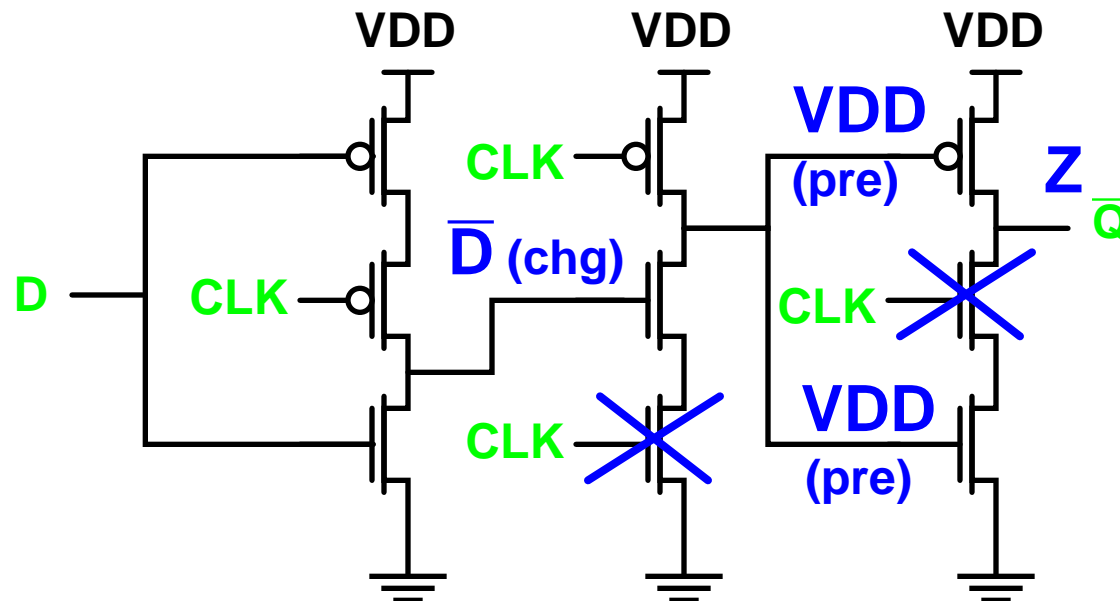


Positive edge-driven register



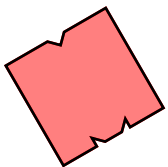
Some Issues

Non-overlapping clocks: “True” Single-Phase Clocked Register



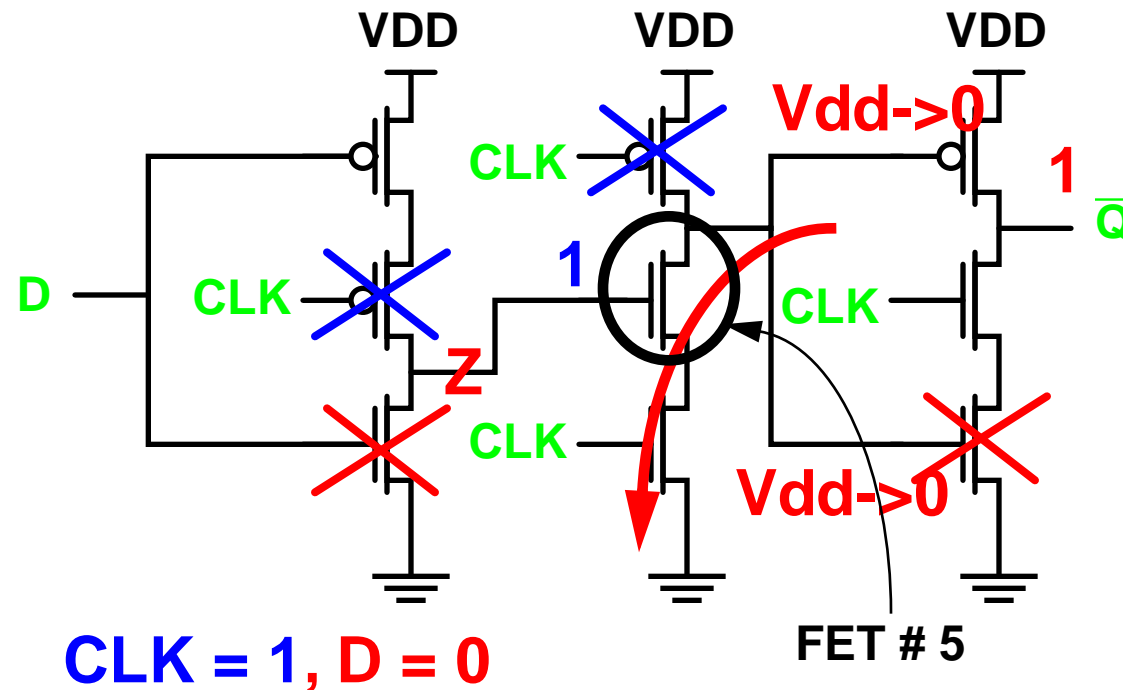
CLK = 0

Output = Z => output is *stable* (dynamic)



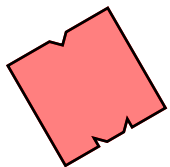
Some Issues

Non-overlapping clocks: “True” Single-Phase Clocked Register



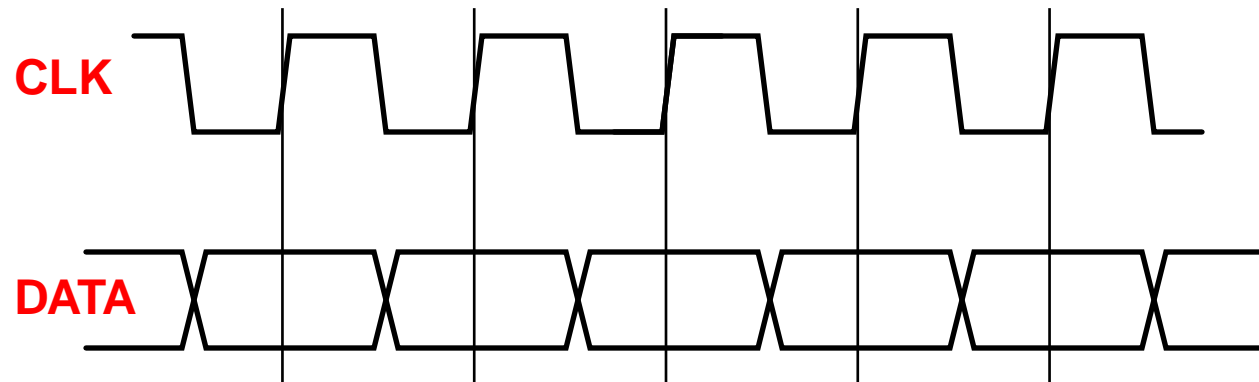
Note: if D is allowed to transition from 0 to 1 too soon after CLK transitions 0->1, it is possible to close FET #5 before the final capacitance discharges ($V_{dd} \rightarrow 0$) ... which would obviously pose a problem.

This represents the *hold time* of this register.



Some Issues

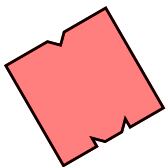
Clock power: Dual-Edge-Triggered Reg.



Note that clock transitions twice as often as data does (actually, even more, unless the data pattern happens to be 01010101010 ...)

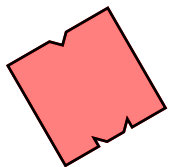
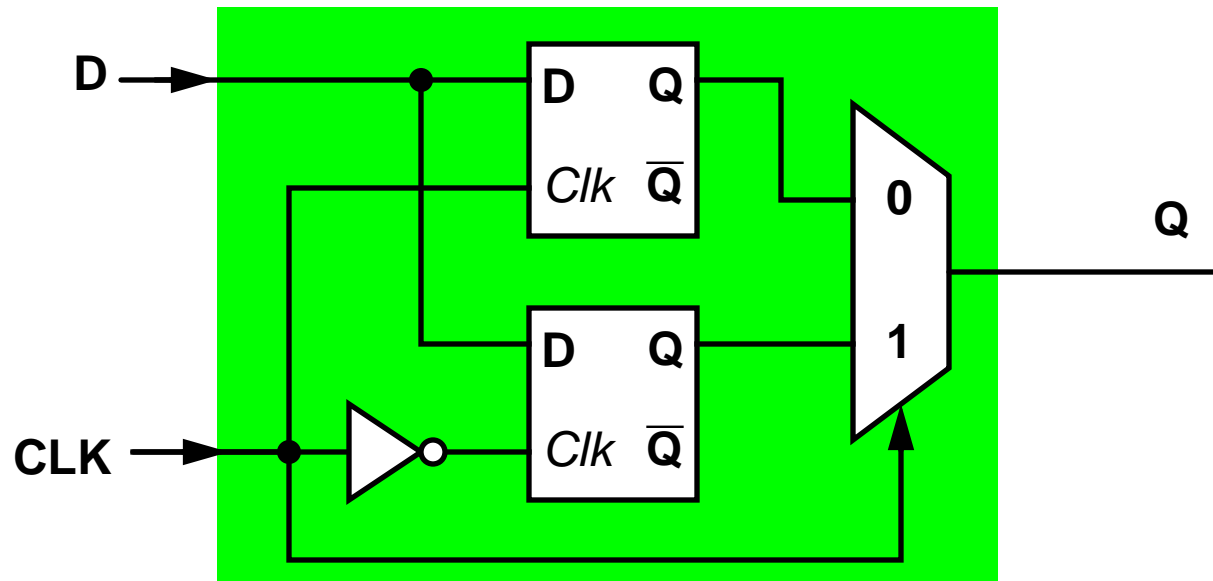
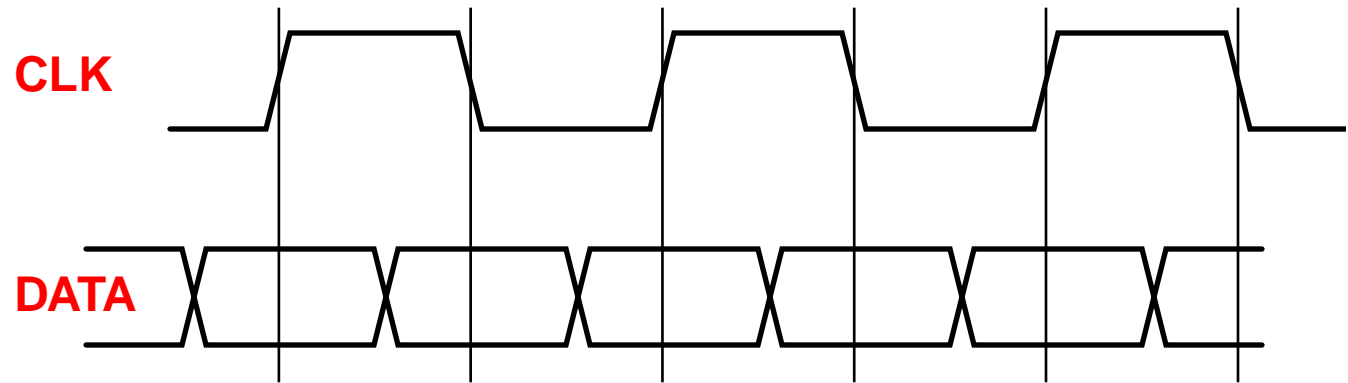
Max data rate = 1Gbps; clock rate = 2GHz

At high frequencies, this is a problem



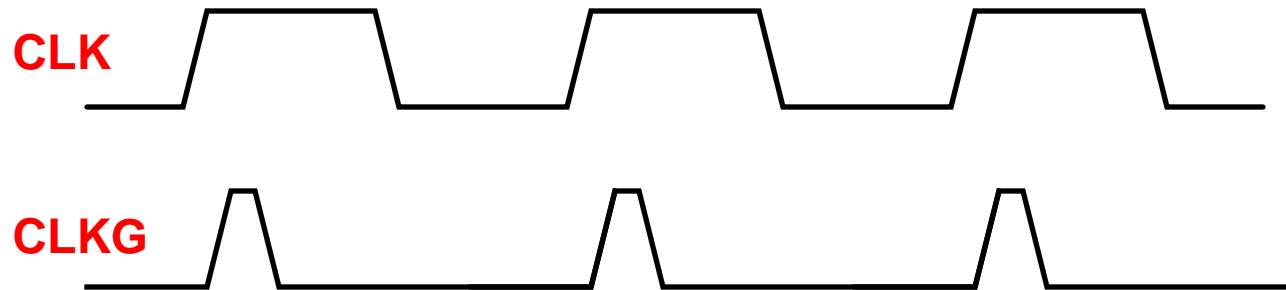
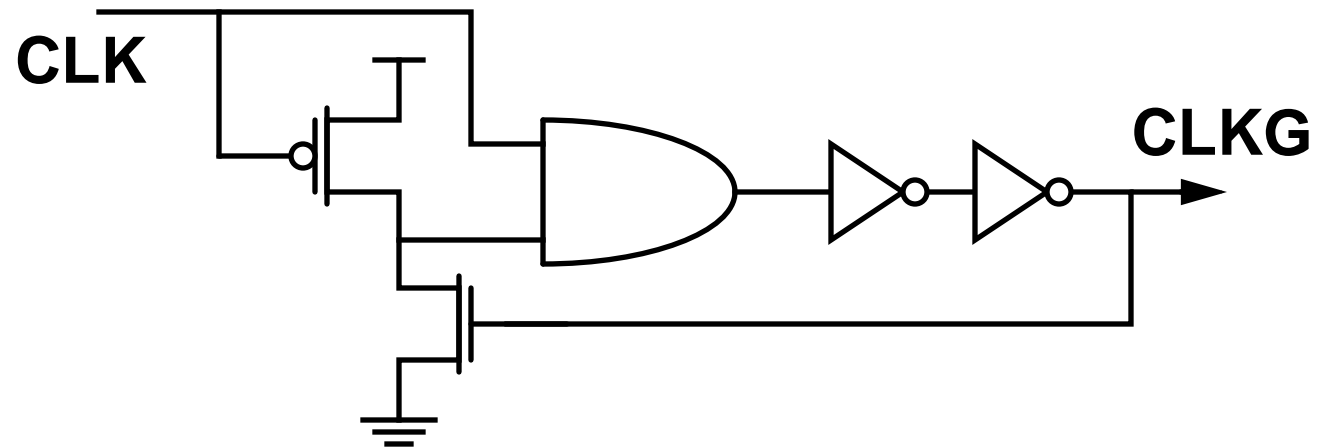
Some Issues

Clock power: Dual-Edge-Triggered Reg.



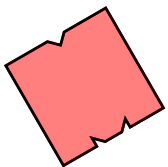
Some Issues

Simplicity, speed of design: Pulse registers



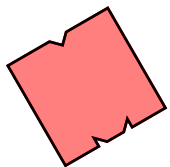
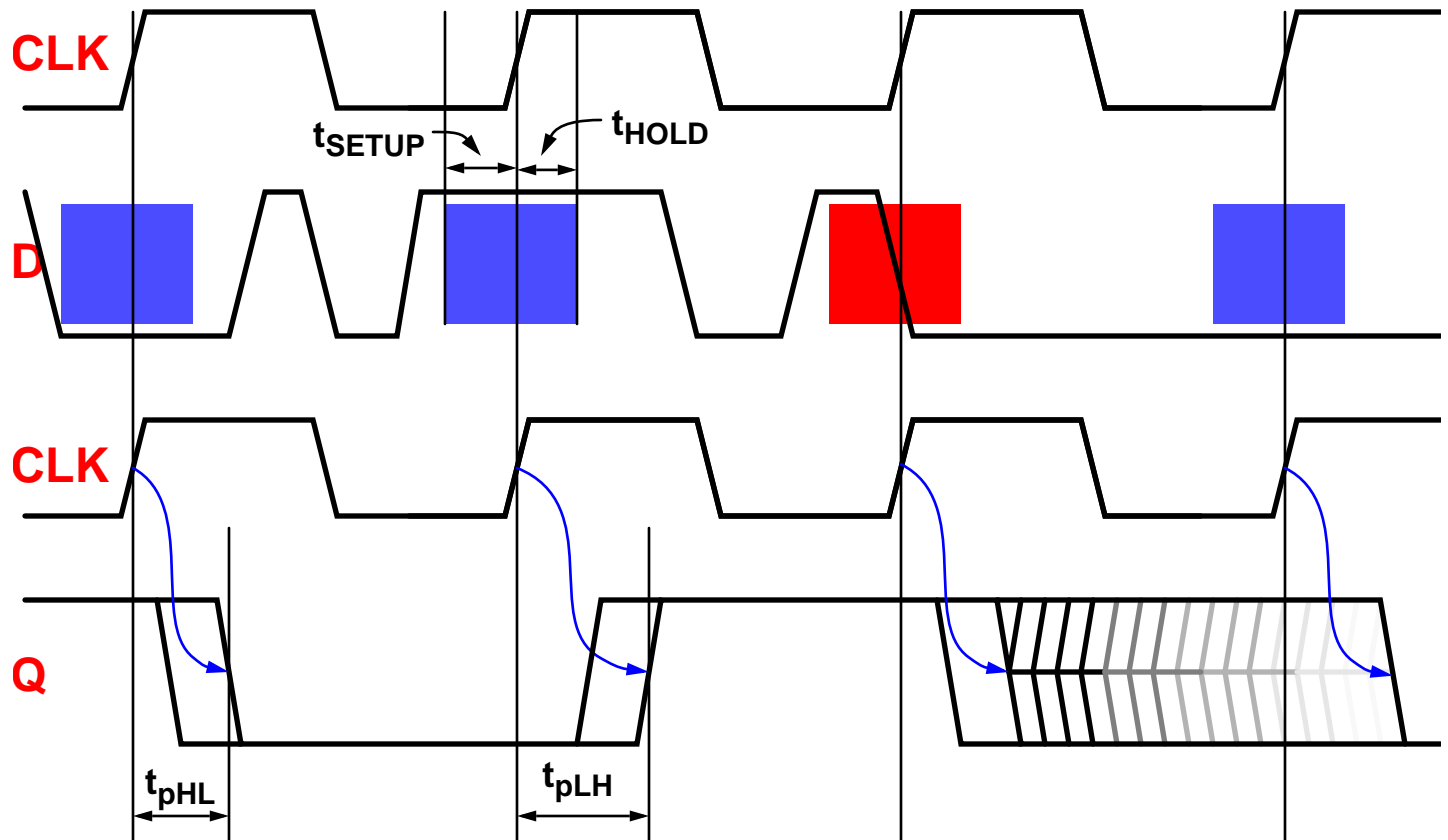
For use with transparent latches: creates *de facto* registers, provided you do thorough timing analysis to guarantee inputs to latch stable during transparent window.

Benefits: latches much faster than registers, use fewer transistors, present lighter load to clock network (leads to lower power consumption).



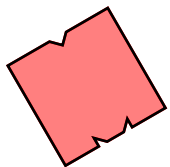
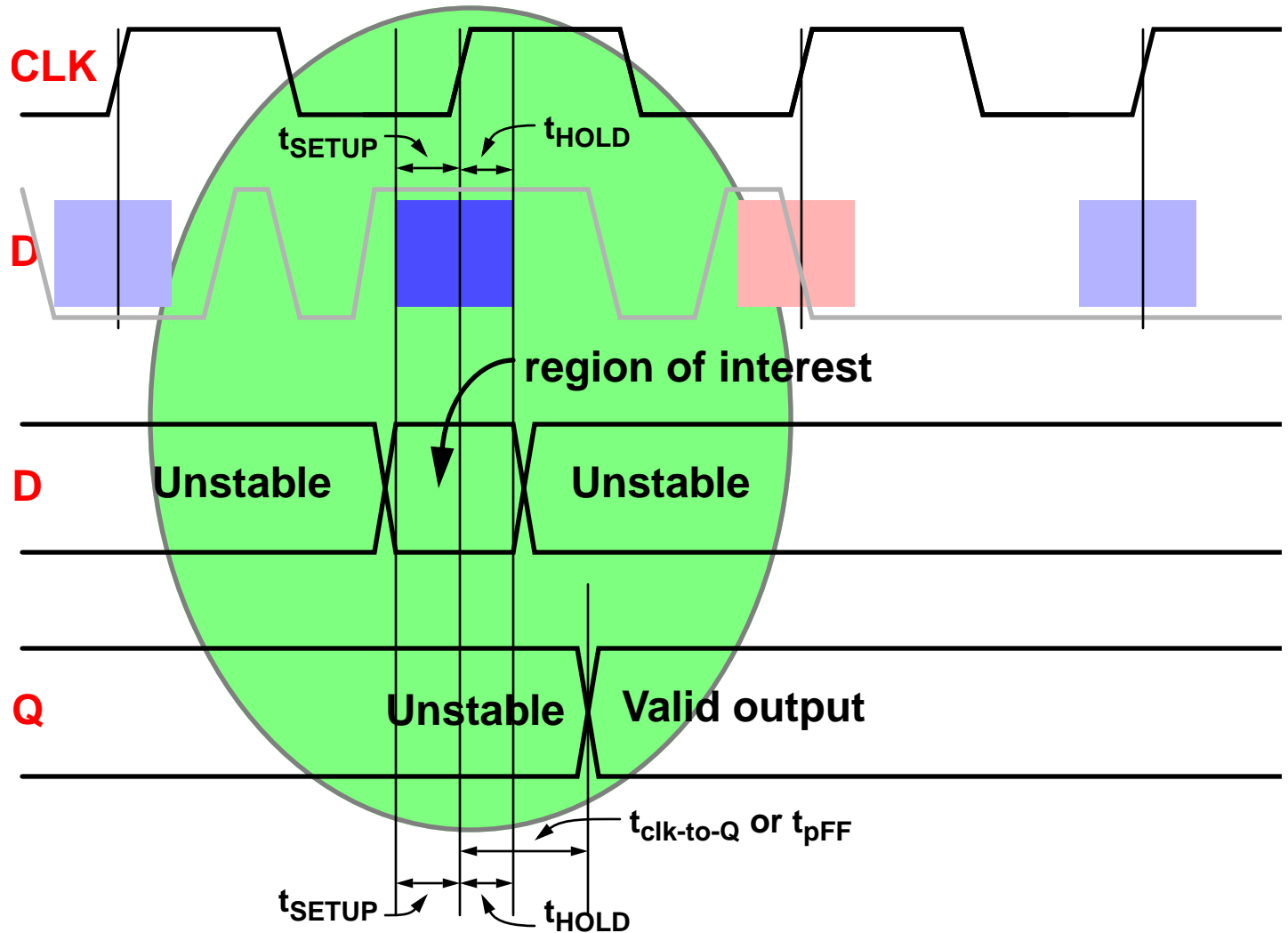
Some Issues

SET-UP and HOLD time, metastability



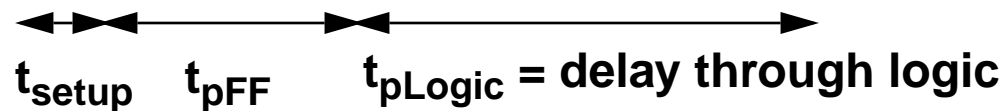
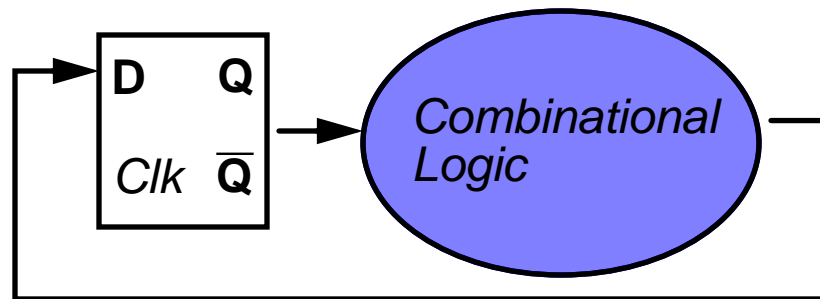
Some Issues

SET-UP and HOLD time, max. clock rate



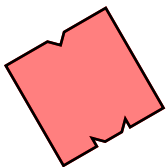
Some Issues

SET-UP and HOLD time, max. clock rate



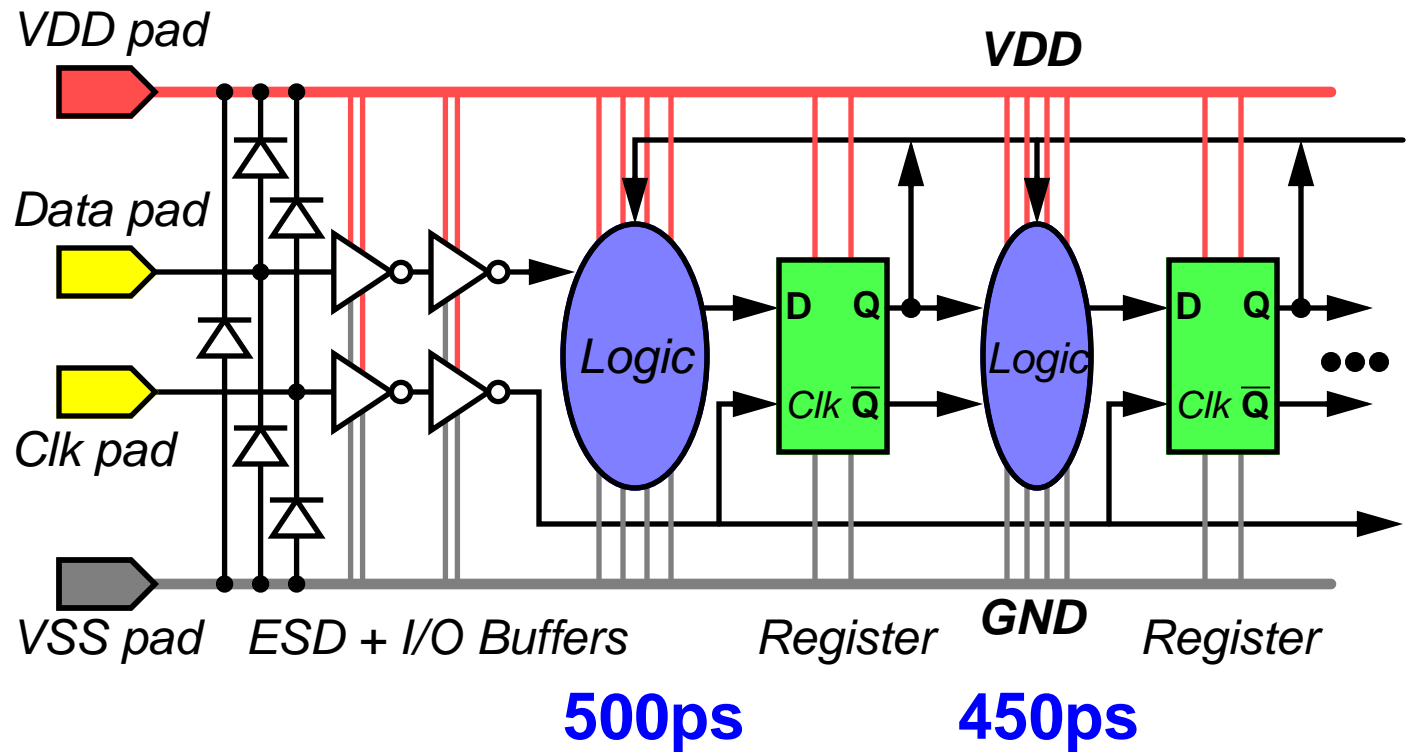
Max. clock frequency:

$$T_{\min} \geq t_{\text{pFF}} + t_{\text{pLogic}} + t_{\text{setup}}$$
$$F_{\max} \leq 1 / (t_{\text{pFF}} + t_{\text{pLogic}} + t_{\text{setup}})$$

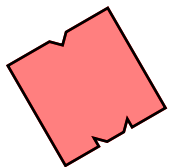


Pipelining

Goal: Increase max. clock rate

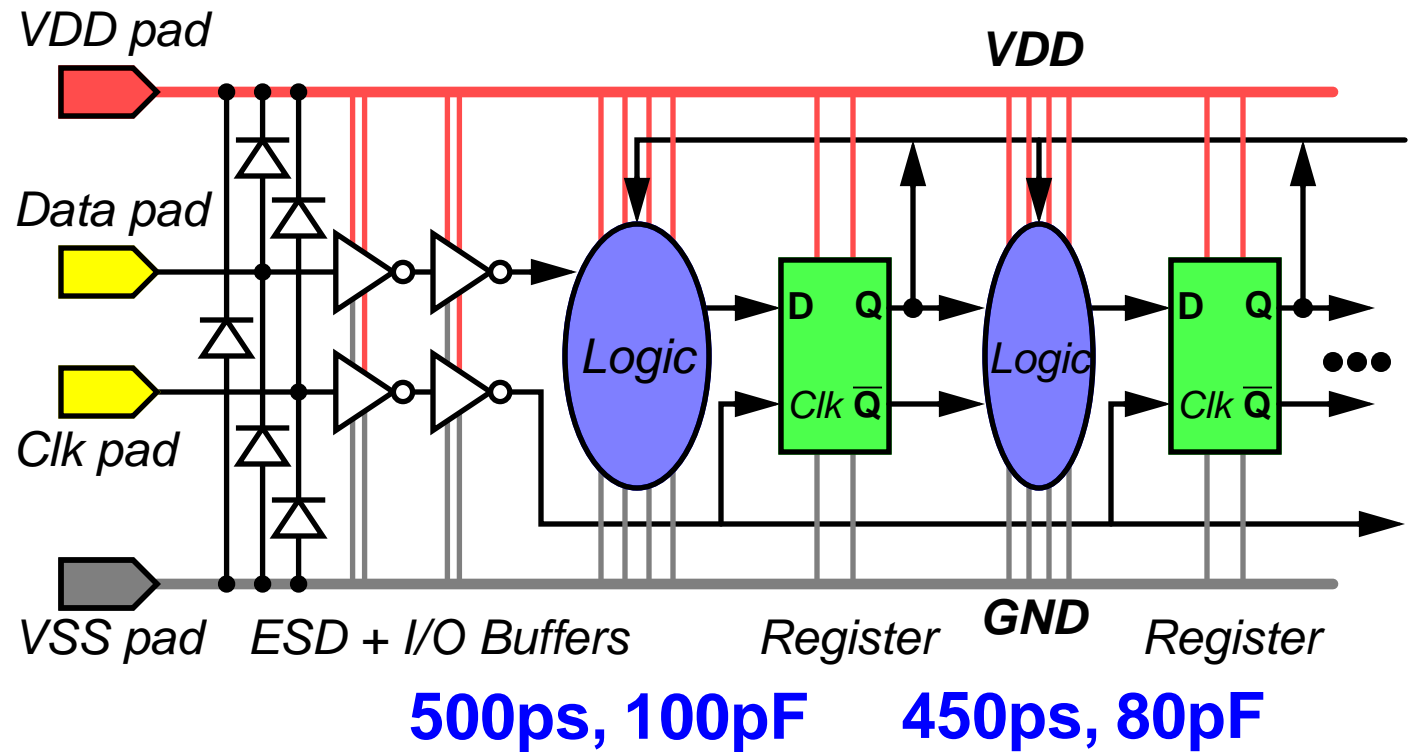


Worst-case logic delay: 950ps vs. 500ps



Pipelining

Goal: Decrease power dissipation



Dynamic Power $\sim CV^2f$

- Can reduce V_{DD} & f_{MAX} and maintain throughput

